PATENT ASSIGNMENT COVER SHEET

Electronic Version v1.1
Stylesheet Version v1.2

EPAS ID: PAT3754483

SUBMISSION TYPE:	CORRECTIVE ASSIGNMENT
NATURE OF CONVEYANCE:	Corrective Assignment to correct the INCORRECT PATENT NUMBER 7261561 AND REPLACE WITH PATENT NUMBER 7231561 previously recorded on Reel 034660 Frame 0188. Assignor(s) hereby confirms the SECURITY AGREEMENT.
RESUBMIT DOCUMENT ID:	503687770

CONVEYING PARTY DATA

Name	Execution Date
XCERRA CORPORATION	12/15/2014
EVERETT CHARLES TECHNOLOGIES LLC	12/15/2014

RECEIVING PARTY DATA

Name:	SILICON VALLEY BANK, AS ADMINISTRATIVE AGENT
Street Address:	3003 TASMAN DRIVE
City:	SANTA CLARA
State/Country:	CALIFORNIA
Postal Code:	95054

PROPERTY NUMBERS Total: 267

Property Type	Number
Patent Number:	4910698
Patent Number:	4902986
Patent Number:	5015989
Patent Number:	4996478
Patent Number:	5091693
Patent Number:	5212443
Patent Number:	5225772
Patent Number:	5068602
Patent Number:	5075569
Patent Number:	5235273
Patent Number:	5122988
Patent Number:	5200696
Patent Number:	5191295
Patent Number:	5311486
Patent Number:	5345186
Patent Number:	5287022

Property Type	Number
Patent Number:	5477139
Patent Number:	5430400
Patent Number:	5447442
Patent Number:	5481550
Patent Number:	5422575
Patent Number:	5461310
Patent Number:	5393230
Patent Number:	5557211
Patent Number:	5552744
Patent Number:	5654657
Patent Number:	5710517
Patent Number:	5646521
Patent Number:	5729146
Patent Number:	5865641
Patent Number:	5684421
Patent Number:	5641315
Patent Number:	5667410
Patent Number:	5913022
Patent Number:	5898314
Patent Number:	5694377
Patent Number:	5717704
Patent Number:	5696773
Patent Number:	5883520
Patent Number:	5708432
Patent Number:	5818248
Patent Number:	5745003
Patent Number:	5694063
Patent Number:	5918198
Patent Number:	5801544
Patent Number:	6092030
Patent Number:	5925145
Patent Number:	5805610
Patent Number:	5930735
Patent Number:	6014764
Patent Number:	6087843
Patent Number:	5964445
Patent Number:	6034558
Patent Number:	5917834

Property Type	Number
Patent Number:	5919270
Patent Number:	5952821
Patent Number:	5944846
Patent Number:	5905403
Patent Number:	6060898
Patent Number:	6332212
Patent Number:	6073263
Patent Number:	6011403
Patent Number:	5955890
Patent Number:	6008683
Patent Number:	5951705
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Patent Number:	5942922
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Patent Number:	6114858
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Patent Number:	6154865
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Patent Number:	6366107
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Patent Number:	6396293
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Patent Number:	6181117
Patent Number:	6230106
Patent Number:	6661836
Patent Number:	6356224
Patent Number:	6331781
Patent Number:	6256757

Property Type	Number
Patent Number:	6304092
Patent Number:	6496953
Patent Number:	6377062
Patent Number:	6484117
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Patent Number:	6330197
Patent Number:	6563298
Patent Number:	6622107
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Patent Number:	6675339
Patent Number:	6788078
Patent Number:	6822435
Patent Number:	6728651
Patent Number:	7017091
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Patent Number:	6942019
Patent Number:	6794861
Patent Number:	7231561
Patent Number:	7035887
Patent Number:	6940271
Patent Number:	7254203
Patent Number:	6665185
Patent Number:	6703825
Patent Number:	7343538
Patent Number:	6836109
Patent Number:	7171598
Patent Number:	7039841
Patent Number:	7059046
Patent Number:	6979994
Patent Number:	7219269
Patent Number:	7171601

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Patent Number:	7092837
Patent Number:	7009382
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Patent Number:	7120840
Patent Number:	6951482
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Patent Number:	7761751
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Patent Number:	7633304
Patent Number:	8239434
Patent Number:	8269480
Patent Number:	7695286
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Patent Number:	RE43739
Patent Number:	7946405
Patent Number:	7969177
Patent Number:	8138779
Patent Number:	8232815
Patent Number:	8324919
Patent Number:	8449002
Patent Number:	8303008
Patent Number:	8297433
Patent Number:	8105119
Patent Number:	8282428
Patent Number:	8476916
Patent Number:	8281483
Patent Number:	8230587
Patent Number:	7982481

Property Type	Number
Patent Number:	8231416
Patent Number:	8648616
Patent Number:	8415941
Patent Number:	8523579
Patent Number:	8504867
Patent Number:	8710856
Application Number:	12200801
Application Number:	12526728
Application Number:	12665531
Application Number:	12681295
Application Number:	12681706
Application Number:	12810716
Application Number:	12858383
Application Number:	12858400
Application Number:	12858406
Application Number:	12887429
Application Number:	12959765
Application Number:	12968023
Application Number:	13124454
Application Number:	13143697
Application Number:	13262625
Application Number:	13618871
Application Number:	13749155
Application Number:	13749199
Application Number:	13749260
Application Number:	13749308
Application Number:	13749332
Application Number:	13749641
Application Number:	14115120
Application Number:	29093915
Application Number:	29201978
Application Number:	61768009
Application Number:	61863618
Application Number:	14185664
Application Number:	14452949
Application Number:	14394252
Application Number:	14529033
Application Number:	61987741

Property Type	Number
Application Number:	62015180
Application Number:	12859059
Application Number:	13950156
Application Number:	14184606
Application Number:	14209646
PCT Number:	US2013772178
PCT Number:	EP2012063109
PCT Number:	US2013914590
PCT Number:	US2013914603
PCT Number:	US2013905010
PCT Number:	US1997008900
PCT Number:	US1997008901
PCT Number:	US2001021531
PCT Number:	US2001031500
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PCT Number:	US2010060868
PCT Number:	US2010061376
PCT Number:	US2013031240
PCT Number:	US2008076720
PCT Number:	US2013917482

CORRESPONDENCE DATA

Fax Number: (800)494-7512

Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.

Phone: 202-370-4750
Email: ipteam@nationalcorp.com
Correspondent Name: DARLENA BARI STARK
Address Line 1: 1025 VERMONT AVE NW, SUITE 1130
Address Line 2: NATIONAL CORPORATE RESEARCH, LTD.
Address Line 4: WASHINGTON, D.C. 20005

ATTORNEY DOCKET NUMBER:	F153146
NAME OF SUBMITTER:	ANDREW NASH
SIGNATURE:	/ANDREW NASH/
DATE SIGNED:	02/24/2016

Total Attachments: 120

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PATENT ASSIGNMENT COVER SHEET

Electronic Version v1.1
Stylesheet Version v1.2

EPAS ID: PAT3153054

SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	SECURITY AGREEMENT

CONVEYING PARTY DATA

Name	Execution Date
XCERRA CORPORATION	12/15/2014
EVERETT CHARLES TECHNOLOGIES LLC	12/15/2014

RECEIVING PARTY DATA

Name:	SILICON VALLEY BANK, AS ADMINISTRATIVE AGENT
Street Address:	3003 TASMAN DRIVE
City:	SANTA CLARA
State/Country:	CALIFORNIA
Postal Code:	95054

PROPERTY NUMBERS Total: 267

Property Type	Number
Patent Number:	4910698
Patent Number:	4902986
Patent Number:	5015989
Patent Number:	4996478
Patent Number:	5091693
Patent Number:	5212443
Patent Number:	5225772
Patent Number:	5068602
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Patent Number:	5235273
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Patent Number:	5191295
Patent Number:	5311486
Patent Number:	5345186
Patent Number:	5287022
Patent Number:	5477139
Patent Number:	5430400
Patent Number:	5447442
Patent Number:	5481550

INTELLECTUAL PROPERTY SECURITY AGREEMENT

This Intellectual Property Security Agreement ("Agreement") is entered into as of December 15, 2014 (the "Effective Date") by and between SILICON VALLEY BANK ("Agent"), as Administrative Agent and each of the undersigned grantors (each a "Grantor", and together the "Grantors").

RECITALS

A. The Lenders have agreed to make certain advances of money and to extend certain financial accommodation to Grantor (the "Loans") in the amounts and manner set forth in that certain Credit Agreement, dated as of the Effective Date, by and among, among others, Grantor, the Guarantors party thereto from time to time, the Lenders party thereto from time to time, Agent, as the Issuing Lender, and Agent, as Administrative Agent for the Lenders (as the same may be amended, modified or supplemented from time to time, the "Credit Agreement"; capitalized terms used herein are used as defined in the Credit Agreement). The Lenders are willing to make the Loans to Grantor, but only upon the condition, among others, that Grantor shall grant to Agent a security interest in certain Copyrights, Trademarks, and Patents (as each term is described below) to secure the obligations of Grantor under the Credit Agreement.

B. Pursuant to the terms of that certain Guarantee and Collateral Agreement, dated as of the Effective Date, by and among, among others, the Grantors and Agent, as Administrative Agent (as the same may be amended, modified or supplemented from time to time, the "Guarantee and Collateral Agreement"), each Grantor has granted to Agent a security interest in all of Grantor's right, title and interest, whether presently existing or hereafter acquired, in, to and under all of the Collateral.

NOW, THEREFORE, for good and valuable consideration, receipt of which is hereby acknowledged, and intending to be legally bound, as collateral security for the prompt and complete payment when due of its obligations under the Credit Agreement, Grantor hereby represents, warrants, covenants and agrees as follows:

AGREEMENT

1. Grant of Security Interest. To secure its obligations under the Credit Agreement, each Grantor grants and pledges to Agent a security interest in all of Grantor's right, title and interest in, to and under its intellectual property (all of which shall collectively be called the "Intellectual Property Collateral"), including, without limitation, the following:

(a) Any trademark and servicemark rights, whether registered or not, applications to register and registrations of the same and like protections, and the entire goodwill of the business of Grantor connected with and symbolized by such trademarks, including without limitation those set forth on Exhibit A attached hereto (collectively, the "Trademarks");

(b) Any and all copyright rights, copyright applications, copyright registrations and like protections in each work or authorship and derivative work thereof, whether published or unpublished and whether or not the same also constitutes a trade secret, now or hereafter existing, created, acquired or held, including without limitation those set forth on Exhibit A attached hereto (collectively, the "Copyrights");

(c) Any and all trade secrets, and any and all intellectual property rights in computer software and computer software products now or hereafter existing, created, acquired or held;

(d) Any and all design rights that may be available to Grantor now or hereafter existing, created, acquired or held;

(e) All patents, patent applications and like protections including, without limitation, improvements, divisions, continuations, renewals, reissues, extensions and continuations-in-part of the same, including without limitation the patents and patent applications set forth on Exhibit B attached hereto (collectively, the "Patents");

(f) Any and all copyright rights, copyright applications, copyright registrations and like protections in each work or authorship and derivative work thereof, whether published or unpublished and whether or not the same also constitutes a trade secret, now or hereafter existing, created, acquired or held, including without limitation those set forth on Exhibit C attached hereto (collectively, the "Copyrights");

(g) Any and all claims for damages by way of past, present and future infringements of any of the rights included above, with the right, but not the obligation, to sue for and collect such damages for said use or infringement of the intellectual property rights identified above;

(h) All licenses or other rights to use any of the Copyrights, Patents, or Trademarks, and all license fees and royalties arising from such use to the extent permitted by such license or rights;

(i) All amendments, extensions, renewals and extensions of any of the Copyrights, Trademarks, or Patents; and

(j) All proceeds and products of the foregoing, including without limitation all payments under insurance or any indemnity or warranty payable in respect of any of the foregoing.

2. Recordation. Grantor authorizes the Commissioner for Patents, the Commissioner for Trademarks and the Register of Copyrights and any other government officials to record and register this Agreement upon request by Agent.

3. Loan Documents. This Agreement has been entered into pursuant to and in conjunction with the Credit Agreement, which is hereby incorporated by reference. The provisions of the Credit Agreement and/or the Guarantee and Collateral Agreement, as

applicable, shall supersede and control over any conflicting or inconsistent provision herein. The rights and remedies of Agent with respect to the Intellectual Property Collateral are as provided by the Credit Agreement, the Guarantee and Collateral Agreement and related documents, and nothing in this Agreement shall be deemed to limit such rights and remedies.

4. Execution in Counterparts. This Agreement may be executed in counterparts (and by different parties hereto in different counterparts), each of which shall constitute an original, but all of which when taken together shall constitute a single contract. Delivery of an executed counterpart of a signature page to this Agreement by facsimile or in electronic (i.e., "pdf" or "tif" format) shall be effective as delivery of a manually executed counterpart of this Agreement.

5. Successors and Assigns. This Agreement will be binding on and shall inure to the benefit of the parties hereto and their respective successors and assigns.

6. Governing Law. This Agreement and any claim, controversy, dispute or cause of action (whether in contract or tort or otherwise) based upon, arising out of or relating to this Agreement and the transactions contemplated hereby and thereby shall be governed by, and construed in accordance with, the laws of the United States and the State of New York, without giving effect to any choice or conflict of law provision or rule (whether of the State of New York or any other jurisdiction).

[Signature page follows.]

IN WITNESS WHEREOF, the parties have caused this Intellectual Property Security Agreement to be duly executed by its officers thereunto duly authorized as of the first date written above.

GRANTORS:

XCERRA CORPORATION, as a Grantor

By:_____

Name:_____

Title:_____

EVERETT CHARLES TECHNOLOGIES LLC, as a Grantor

By:_____

Name:_____

Title:_____

ADMINISTRATIVE AGENT:

SILICON VALLEY BANK

By: _____

Name: Mike Shuhy

Title: Director

EXHIBIT A

Copyrights

See Attached

United States	TX3808618	1/7/1997	Scorpion HV90 SMT bare board test system : user manual and guide to operations.
United States	TX4445331	12/30/1996	Computer aided processing.
United States	TX4455170	1/7/1997	VIPER II Computer Program
United States	TX4456105	1/13/1997	CAF-NT 1.20.
United States	TX4471772	12/30/1996	Fault Viewer.
United States	TX4483584	1/7/1997	Krhyi.
United States	TX4494204	6/13/1997	DetECT.
United States	TX4498668	1/7/1997	DETECT II Computer Program
United States	TX4504899	6/27/1997	NODE Viewer Computer Program Plus Sealer Notes (Various Releases)
United States	TX4522819	1/7/1997	Computer aided fixturing. By Gregory J. Miczek, John E. Robertson & Matthew T. Miczek.
United States	TX4554235	12/30/1996	9090 bare board test system : user manual and guide to operations.
United States	TX778271	1/7/1997	CAF Computer Program Plus Release Notes Text of User's Manual and Release Notes
United States	TX5794027	6/24/2003	MPS (Manufacturing Process Software)
United States	TX5226237	6/19/2000	VG organizer; computer program

EXHIBIT B

Patents

See Attached

Jurisdiction	Patent No.	Issue Date	Inventor	Title
USA	4910698	3/20/1990	MCCARTNEY, A.	A SINE WAVE GENERATOR USING A CORDIC ALGORITHM
USA	4902986	2/20/1990	LESMEISTER, G.	PHASED LOCKED LOOP TO PROVIDE PRECISE FREQUENCY AND PHASE TRACKING OF TWO SIGNALS
USA	5015989	5/14/1991	WOHLFARTH, P.; BUCHANON, G.	FILM RESISTOR WITH ENHANCED TRIMMING CHARACTERISTICS
USA	4996478	2/26/1991	POPE, K.	APPARATUS FOR CONNECTING AN IC DEVICE TO A TEST SYSTEM
USA	5091693	2/25/1992	BERRY, T.; HILL, M.; DELANEY, L.; STAFFELBACH, R.	DUAL-SIDED TEST HEAD HAVING FLOATING CONTACT SURFACES
USA	5212443	5/18/1993	WEST, B.; GRAEVE, E.	EVENT SEQUENCER FOR AUTOMATIC TEST EQUIPMENT
USA	5225772	7/06/1993	CHEUNG, D.; GRAEVE, E.	AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE
USA	5068602	11/26/1991	MIELKE, J.	DUT BOARD FOR A SEMICONDUCTOR DEVICE TESTER HAVING A RECONFIGURABLE COAXIAL INTERCONNECT GRID AND METHOD OF USING SAME
USA	5075569	12/24/1991	BRANSON, C.	OUTPUT DEVICE CIRCUIT AND METHOD TO MINIMIZE IMPEDANCE FLUCTUATIONS DURING CROSSOVER
USA	5235273	8/10/1993	AKAR, A.; JENNINGS, P.	APPARATUS FOR SETTING PIN DRIVER/SENSOR REFERENCE VOLTAGE LEVEL
USA	5122988	6/16/1992	GRAEVE, E.	DATA STREAM SMOOTHING USING A FIFO MEMORY

USA	5200696	4/06/1993	MENIS, D.; VITALE, H.; BURLISON, P.; DEHAVEN, W.	TEST SYSTEM APPARATUS WITH SCHOTTKY DIODES WITH PROGRAMMABLE VOLTAGES
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Pending Patent Applications of Xcerra Corporation

Jurisdiction	Serial No.	Filing Date	Inventor	Title
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Patents

OWNER/ ASSIGNEE	COUNTRY	APPLICATION NUMBER	APPLICATION DATE	REGISTRATION/ PUBLICATION NUMBER	REGISTRATION/ PUBLICATION DATE	TITLE	STATUS
Delaware Capital Formation, Inc.	United States	08/126179	9/23/1993	5447442	9/5/1995	Compliant electrical connectors	
Delaware Capital Formation, Inc.	United States	08/224006	4/5/1994	5422575	6/6/1995	Test fixture with adjustable bearings and optical alignment system	
Delaware Capital Formation, Inc.	United States	08/462229	6/5/1995	5557211	9/17/1996	Vacuum test fixture for printed circuit boards	
Delaware Capital Formation, Inc.	United Kingdom	9401551.8	1/27/1994	2274920	11/27/1996	Marker probe	
Delaware Capital Formation, Inc.	Germany	4404115.2	2/9/1994	4404115	7/29/1999	Prufvorrichtung zum Prufen von gedruckten Schaltungskarten (German)	
Delaware Capital Formation, Inc.	United States	08/292054	8/16/1994	5493230	2/20/1996	Retention of test probes in translator fixtures	
Delaware Capital Formation, Inc.	United States	08/558687	11/16/1995	5641315	6/24/1997	Telescoping spring probe	
Delaware Capital Formation, Inc.	United States	08/561395	11/21/1995	5667410	9/16/1997	One-piece compliant probe	
Delaware Capital Formation, Inc.	United States	08/531720	9/21/1995	5729146	3/17/1998	Quick stacking translator fixture	
Delaware Capital Formation, Inc.	United States	08/783467	1/16/1997	5801544	9/1/1998	Spring probe and method for biasing	
Delaware Capital Formation, Inc.	United Kingdom	199800596.0	1/14/1998	2323222	4/18/2001	Spring probe and method for biasing	
Delaware Capital Formation, Inc.	Taiwan	86109649	7/9/1997	105627	7/1/1999	Spring Probe and Method for	

						Biasing	
Delaware Capital Formation, Inc.	Germany	19801269.1	1/15/1998	19801269	7/1/1999	Electrical circuit testing probe	
Delaware Capital Formation, Inc.	France	1998370	1/15/1998	2758395	6/23/2000	SONDE A RESSOR T POUR TESTS ELECTRI QUES (French)	
Delaware Capital Formation, Inc.	United States	08/688189	7/29/1996	5818248	10/6/1998	Loaded board test fixture with integral translator fixture for testing closely spaced test sites	
Delaware Capital Formation, Inc.	European	1997935151	7/29/1997	855037	12/7/2005	LOADED BOARD DROP PIN FIXTURE	
Delaware Capital Formation, Inc.	United States	08/536131	9/29/1995	5865641	2/2/1999	Solid spring electrical contacts for electrical connector s and probes	
Delaware Capital Formation, Inc.	United Kingdom	199514007.5	7/10/1995	2291544	10/2/1996	Electrical connector s	
Delaware Capital Formation, Inc.	Japan	1995176316	7/12/1995	2718425	11/14/1997	Solid Spring Electrical Contacts for Electrical Connector s and Probes	
Delaware Capital Formation, Inc.	Germany	19525390.6	7/12/1995	19525390	10/2/2003	Elektrisch e Verbindu ngsvorric htung (German)	
Delaware Capital Formation, Inc.	France	9508309	7/10/1995	9508309	6/12/1998	CONTAC TS ELECTRI QUES A RESSOR T PLEIN POUR DES CONNEC TEURS ET DES SONDES	

						ELECTRIQUES (French)	
Delaware Capital Formation, Inc.	United States	29/093915	9/22/1998	D422230	4/4/2000	Coaxial Test Probe	
Delaware Capital Formation, Inc.	United Kingdom	2082174	3/22/1999	2082174	6/2/1999	Coaxial Test Probe	
Delaware Capital Formation, Inc	Germany	49902980.1	3/19/1999	49902980.1	10/9/1999	Coaxial Test Probe	
Delaware Capital Formation, Inc.	France	991814	3/18/1999	991814	9/3/1999	COAXIAL TEST PROBE	
Delaware Capital Formation, Inc.	Finland	M19990247	3/18/1999	20659	10/29/1999	Coaxial Test Probe	
Delaware Capital Formation, Inc.	United States	08/606593	2/26/1996	5898314	4/27/1999	Translator fixture with force applying blind pins	
Delaware Capital Formation, Inc.	Italy	TO97A000158	2/25/1997	1291147	12/29/1998	ATTREZZATURA PER LA TRASLAZIONE DI SEGNALI CON SPINE CIECHE PER L'APPLICAZIONE DI FORZA (Italian)	
Delaware Capital Formation, Inc.	Germany	19707485.5	2/25/1997	19707485	1/24/2008	Haltevorrichtung und Haltebaugruppe fur ein Leiterplatten-Prufgerat (German)	
Delaware Capital Formation, Inc.	Taiwan	87118577	11/17/1998	112013	2/1/2000	Scan test machine for densely spaced test sites	
Delaware Capital Formation, Inc.	Italy	2001250038.5	2/2/2001	1122546	7/9/2008	Scan Test Machine for Densely Spaced Test Sites	

Delaware Capital Formation, Inc.	European	2001250038.5	2/2/2001	1122546	7/9/2008	Scan test machine for densely spaced test sites	
Delaware Capital Formation, Inc.	United States	09/207740	12/8/1998	6194908	2/27/2001	Test fixture for testing backplanes or populated circuit boards	
Delaware Capital Formation, Inc.	United States	08-662671	6/14/1996	5883520	3/16/1999	Retention of test probes in translator fixtures	
Delaware Capital Formation, Inc.	United States	09/207741	12/8/1998	6366107	4/2/2002	Loading mechanism for automated verification and repair station	
Delaware Capital Formation, Inc.	WIPO	1997US8900	5/23/1997	1998040752	9/17/1998	PERIPHERALLY LEADED PACKAGE TEST CONTACTOR	
Delaware Capital Formation, Inc.	WIPO	1997US8901	5/23/1997	1998013695	4/2/1998	GRID ARRAY PACKAGE TEST CONTACTOR	
Delaware Capital Formation, Inc.	WIPO	2001US21531	7/5/2001	2002004961	5/23/2002	SELF-RETAINED SPRING PROBE	
Delaware Capital Formation, Inc.	United States	09/614422	7/12/2000	6462567	10/8/2002	Self-retained spring probe	
Delaware Capital Formation, Inc.	United States	09/253320	2/18/1999	6396293	5/28/2002	SELF-CLOSING SPRING PROBE	
Delaware Capital Formation, Inc.	United Kingdom	200021622.6	3/16/1999	2351398	7/25/2001	SPRING PROBE	
Delaware Capital Formation, Inc.	United Kingdom	200021621.8	3/16/1999	2356744	3/13/2002	SPRING PROBE	
Delaware Capital Formation, Inc.	United Kingdom	200021623.4	3/16/1999	2351399	7/25/2001	SPRING PROBE ASSEMBLIES	
Delaware Capital Formation,	United Kingdom	9905858.8	3/16/1999	2347023	7/25/2001	SPRING PROBE	

Inc.							
Delaware Capital Formation, Inc.	Taiwan	88105387	4/3/1999	177029	12/27/2003	Spring probe	
Delaware Capital Formation, Inc.	Taiwan	90116956	8/22/2001	169399	4/29/2003	Self-retained spring probe	
Delaware Capital Formation, Inc.	Japan	1999159442	6/7/1999	3210645	7/13/2001	Spring Probe	
Delaware Capital Formation, Inc.	Italy	04078167.6	11/18/2004	1510827	8/15/2007	Self-Closing Spring Probe	
Delaware Capital Formation, Inc.	Italy	99302847.1	4/13/1999	1037055	4/5/2006	Spring Probe	
Delaware Capital Formation, Inc.	Ireland	04078167.6	11/18/2004	1510827	8/15/2007	Self-Closing Spring Probe	
Delaware Capital Formation, Inc.	Hong Kong	2011105237.1	7/27/2001	1035030	11/15/2002	SPRING PROBE	
Delaware Capital Formation, Inc.	Hong Kong	03107255.2	10/9/2003	HK1054984	4/29/2011	Self-Retained Spring Probe (Amended)	
Delaware Capital Formation, Inc.	Hong Kong	1104426.5	6/27/2001	1033977	5/10/2002	SPRING PROBE ASSEMBLIES	
Delaware Capital Formation, Inc.	Hong Kong	1104425.6	6/27/2001	1033976	3/22/2002	SPRING PROBE	
Delaware Capital Formation, Inc.	Hong Kong	1101340.4	2/23/2001	1030455	3/22/2002	SPRING PROBE	
Delaware Capital Formation, Inc.	Germany	69930717.1	4/13/1999	69930717.1	1/25/2007	Spring Probe	
Delaware Capital Formation, Inc.	Germany	04078167.6	4/13/1999	1510827	8/15/2007	SPRING PROBE	
Delaware Capital Formation, Inc.	France	99302847.1	4/13/1999	1037055	4/5/2006	Spring Probe	
Delaware Capital Formation, Inc.	France	04078167.6	4/13/1999	1510827	8/15/2007	Spring Probe	
Delaware Capital Formation, Inc.	European	1999302847	4/13/1999	1037055	4/5/2006	Spring probe	

Delaware Capital Formation, Inc.	European	2004078167	4/13/1999	1510827	8/15/2007	Spring probe	
Delaware Capital Formation, Inc.	European	2001950967	7/5/2001	1299735	1/12/2011	SELF-RETAINED SPRING PROBE	
Delaware Capital Formation, Inc.	WIPO	2001US31500	10/10/2001	2003031995	4/17/2003	COAXIAL TILT PIN FIXTURE FOR TESTING HIGH FREQUENCY CIRCUIT BOARDS	
Delaware Capital Formation, Inc.	United States	09/991199	11/16/2001	6788078	9/7/2004	Apparatus for scan testing printed circuit boards	
Delaware Capital Formation, Inc.	Korea, South	2002-0071079	11/15/2002	0560089	3/6/2006	Apparatus for Scan Testing Printed Circuit Boards	
Delaware Capital Formation, Inc.	Ireland	02025085	11/12/2002	1312930	5/21/2003	Apparatus for Scan Testing Printed Circuit Boards	
Delaware Capital Formation, Inc.	European	2002025085.8	11/12/2002	1312930	1/17/2007	Apparatus for scan testing printed circuit boards	
Delaware Capital Formation, Inc.	United States	10/454930	6/5/2003	7059046	6/13/2006	Method for producing a captive wired test fixture and fixture therefor	
Delaware Capital Formation, Inc.	United States	11/373595	3/9/2006	7424775	9/16/2008	Captive wired test fixture	
Delaware Capital Formation, Inc.	European	2003253864.7	6/18/2003	1376141	5/25/2011	Method for producing a captive wired test fixture and fixture therefor	
Delaware Capital Formation,	United States	10/897182	7/22/2004	7071716	7/4/2006	Apparatus for scan testing	

Inc.						printed circuit boards	
Delaware Capital Formation, Inc.	WIPO	2006US22311	6/8/2006	2006135680	12/21/2006	Electrical Contact Probe with Compliant Internal Interconn ect	
Delaware Capital Formation, Inc.	United States	11/450231	6/8/2006	7256593	8/14/2007	Electrical contact probe with compliant internal interconne ct	
Delaware Capital Formation, Inc.	Singapore	200718278.5	6/8/2006	138004	12/31/2009	Electrical Contact Probe with Compliant Internal Interconn ect	
Delaware Capital Formation, Inc.	Philippines	2007502628	6/8/2006	12007502628	4/18/2011	Electrical Contact Probe with Compliant Internal Interconn ect	
Delaware Capital Formation, Inc.	Malaysia	PI20071950	11/9/2007	144789	11/15/2011	Electrical Contact Probe with Compliant Internal Interconn ect	
Delaware Capital Formation, Inc.	Korea, South	20087000738	6/8/2006	101012712	1/27/2011	Compliant Electrical Interconn ect and Electrical Contact Probe	
Delaware Capital Formation, Inc.	Japan	2008515918	6/8/2006	4585024	9/10/2010	Electrical Contact Probe with Compliant Internal Interconn ect	
Delaware Capital Formation, Inc.	China	200680020653	6/8/2006	101501509	8/5/2009	Electrical contact probe with compliant internal interconne ct	
Delaware Capital Formation,	Taiwan	88115508	9/8/1999	173745	2/21/2003	Scan test apparatus for	

Inc.						continuity testing of bare printed circuit boards	
Delaware Capital Formation, Inc.	WIPO	2008US76720	9/17/2008	2009039205	3/26/2009	SPRING CONTACT ASSEMBY	
Delaware Capital Formation, Inc.	United States	12/206659	9/8/2008	7862391	1/4/2011	Spring contact assembly	
Delaware Capital Formation, Inc.	Taiwan	97135610	9/17/2008	I375362	10/21/2012	Spring Contact Assembly	
Delaware Capital Formation, Inc.	Singapore	201001575-8	9/17/2008	159827	7/31/2012	Spring Contact Assembly	
Delaware Capital Formation, Inc.	Philippines	12010500312	9/17/2008			Spring Contact Assembly	
Delaware Capital Formation, Inc.	Malaysia	PI2010001071	9/17/2008			Spring Contact Assembly	
Delaware Capital Formation, Inc.	Korea, South	1020107004086	2/24/2010	10-1145283	5/4/2012	Spring Contact Assembly	
Delaware Capital Formation, Inc.	Japan	2010525927	9/17/2008	4988927	5/11/2012	Spring Contact Assembly	
Delaware Capital Formation, Inc.	European	2008831781.3	9/17/2008	2191544	6/2/2010	Spring Contact Assembly	
Delaware Capital Formation, Inc.	China	200880102509	9/17/2008	200880102509	12/12/2012	Spring Contact Assembly	
Delaware Capital Formation, Inc.	China	2012102396875	7/11/2012	102738627	10/17/2012	Spring Contact Assembly	
Delaware Capital Formation, Inc.	WIPO	2008US076706	9/17/2008	2009039194	3/26/2009	SEMICONDUCTOR ELECTROMECHANICAL CONTACT	
Delaware Capital Formation, Inc.	United States	12/204741	9/4/2008	7695286	4/13/2010	Semiconductor electromechanical contact	
Delaware Capital Formation, Inc.	Taiwan	97135607	9/17/2008	200922053	5/16/2009	Semiconductor Electromechanical Contact	

Delaware Capital Formation, Inc.	Malaysia	PI2010001070	9/17/2008			Semicond uctor Electrome chanical Contact	
Delaware Capital Formation, Inc.	European	2008831540.3	9/17/2008	2206196	7/14/2010	Semicond uctor Electrome chanical Contact	
Delaware Capital Formation, Inc.	China	200880107681	9/17/2008	101803116	8/11/2010	Semicond uctor electrome chanical contact	
Delaware Capital Formation, Inc.	WIPO	2010US21252	1/15/2010	2010088077	8/5/2010	Flat Plunger Round Barrel Probe	
Delaware Capital Formation, Inc.	United States	12/683346	1/6/2010	8105119	1/31/2012	Flat Plunger Round Barrel Test Probe	
Delaware Capital Formation, Inc.	Taiwan	99102240	1/27/2010	201037319	10/16/2010	Flat plunger round barrel test probe (English)	
Delaware Capital Formation, Inc.	Mexico	10/2011/007730	1/15/2010	310151	6/3/2013	Flat Plunger Round Barrel Test Probe	
Delaware Capital Formation, Inc.	Korea, South	20117019121	1/15/2010	2011-0105401	9/26/2011	Flat Plunger Round Barrel Test Probe	
Delaware Capital Formation, Inc.	European	2010736210.5	1/15/2010	2384443	11/9/2011	Flat Plunger Round Barrel Test Probe	
Delaware Capital Formation, Inc.	China	201080005905.8	1/15/2010			Flat Plunger Round Barrel Test Probe	
Delaware Capital Formation, Inc.	WIPO	2010US28727	3/25/2010	2010111532	9/30/2010	Scrub Inducing Compliant Electrical Contact	
Delaware Capital Formation, Inc.	United States	12/629790	12/2/2009	8324919	12/4/2012	Scrub inducing compliant electrical contact (English)	
Delaware Capital	Taiwan	99108338	3/22/2010	201043967	12/16/2010	Scrub inducing	

Formation, Inc.						compliant electrical contact (English)	
Delaware Capital Formation, Inc.	Korea, South	20117023661	10/7/2011	2011-0124367	11/16/2011	Scrub Inducing Compliant Electrical Contact	
Delaware Capital Formation, Inc.	European	2010756871.9	3/25/2010	2411820	2/1/2012	Scrub Inducing Compliant Electrical Contact	
Delaware Capital Formation, Inc.	China	201080019928.4	3/25/2010	102422170	4/18/2012	Scrub Inducing Compliant Electrical Contact	
Delaware Capital Formation, Inc.	WIPO	2010US60868	12/16/2010	2011075599	6/23/2011	Wiring Board for Testing Loaded Printed Circuit Boards	
Delaware Capital Formation, Inc.	United States	12/959765	12/3/2010	20110148451	6/23/2011	Wiring Board for Testing Loaded Printed Circuit Boards	
Delaware Capital Formation, Inc.	Thailand	1201002875	12/16/2010			Wiring Board for Testing Loaded Printed Circuit Boards	
Delaware Capital Formation, Inc.	Taiwan	99143251	12/10/2010	201135249	10/16/2011	Wiring board for testing loaded printed circuit board (English)	
Delaware Capital Formation, Inc.	Malaysia	PI2012002698	12/16/2010			Wiring Board for Testing Loaded Printed Circuit Boards	
Delaware Capital Formation, Inc.	European	2010838264.9	12/16/2010	2517031	10/31/2012	WIRING BOARD FOR TESTING LOADED PRINTED CIRCUIT BOARD (English)	
Delaware Capital Formation, Inc.	China	201080057353.5	12/16/2010	102656468	9/5/2012	Wiring Board for Testing Loaded Printed	

						Circuit Boards	
Delaware Capital Formation, Inc.	United States	12/968023	12/14/2010	20110175636	7/21/2011	Terminal for Flat Test Probe	
Delaware Capital Formation, Inc.	Taiwan	99145850	12/24/2010	201140069	11/16/2011	Terminal for flat test probe (English)	
Delaware Capital Formation, Inc.	WIPO	2010US61376	12/20/2010	2011087764	7/21/2011	Loaded Printed Circuit Board Test Fixture and Method for Manufact uring the Same	
Delaware Capital Formation, Inc.	United States	12/963322	12/8/2010			Loaded Printed Circuit Board Test Fixture and Method for Manufact uring the Same	
Delaware Capital Formation, Inc.	Thailand	1201002876	12/20/2010			Loaded Printed Circuit Board Test Fixture and Method for Manufact uring the Same	
Delaware Capital Formation, Inc.	Taiwan	99144733	12/20/2010	201135241	10/16/2011	Loaded printed circuit board test fixture and method for manufactu ring the same (English)	
Delaware Capital Formation, Inc.	Malaysia	PI2012002701	12/20/2010			Loaded Printed Circuit Board Test Fixture and Method for Manufact uring the	

						Same	
Delaware Capital Formation, Inc.	European	2010843524.9	12/20/2010	2517030	10/31/2012	Loaded Printed Circuit Board Test Fixture and Method for Manufact uring the Same	
Delaware Capital Formation, Inc.	China	201080058667.7	12/20/2010	102725646	10/10/2012	Loaded Printed Circuit Board Test Fixture and Method for Manufact uring the Same	
Delaware Capital Formation, Inc.	United States	12/912683	10/26/2010	8231416	7/31/2012	Spring contact assembly (English)	
Delaware Capital Formation, Inc.	United States	13/618871	9/14/2012	2013-0069685-A1	3/21/2013	Integrated Circuit Test Socket having Test Probe Inserts	
Delaware Capital Formation, Inc.	United States	13/546980	7/11/2012	8523579	09/03/2013	Spring Contact Assembly	
Delaware Capital Formation, Inc.	United States/WIPO	PCT/US2013/03 1240	3/14/2013		to be published 10/13/2013	TEST PROBE ASSEMB LY AND RELATE D METHO DS	
atg Luther & Maelzer GmbH	Germany	195 41 307.5-09	6/11/1995			Verfahren und Vorrichtu ng zum Prüfen einer elektrisch en Leiteranor dnung	granted
atg Luther & Maelzer GmbH	Germany	596 10 371.9-08	4/11/1996	0 772 054		METHO D AND APPARA TUS FOR TESTING AN	national phase (EP)

						ELECTRICAL CONDUCTOR ASSEMBLY	
atg test systems GmbH & Co. KG	Europe	96 117 642.7	4/11/1996	0 772 054		METHOD AND APPARATUS FOR TESTING AN ELECTRICAL CONDUCTOR ASSEMBLY	granted
atg test systems GmbH & Co. KG	France	96 117 642.7	4/11/1996	0 772 054		METHOD AND APPARATUS FOR TESTING AN ELECTRICAL CONDUCTOR ASSEMBLY	national phase (EP)
atg test systems GmbH & Co. KG	Great Britain	772054	4/11/1996			Electric Conductor Arrangement	national phase (EP)
atg test systems GmbH & Co. KG	Italy	96 117 642.7	4/11/1996	0 772 054		METHOD AND APPARATUS FOR TESTING AN ELECTRICAL CONDUCTOR ASSEMBLY	national phase (EP)
atg test systems GmbH & Co. KG	Japan	293833/1996	6/11/1996	183195		Method and Apparatus for Testing an Electrical Conductor Assembly	granted
DTG International GmbH	Germany	10 2010 023 187.8-35	9/6/2010			Vorrichtung und Verfahren zum Untersuchen von Leiterplatten	examination request filed
DTG International GmbH	Taiwan, R.O.C.	100119996	8/6/2011			Apparatus and method for the testing of circuit boards	filed

DTG International GmbH	Germany	DE 10 2011 051 607.7	6/7/2011			Adapter for a test device, and test device for the testing of circuit boards	published
DTG International GmbH	Taiwan, R.O.C.	101122398	06/22/2012			Adapter for a test device, and test device for the testing of circuit boards	filed
DTG International GmbH	WIPO/PCT	PCT/EP2012/063 109	5/7/2012			Adapter for a test device, and test device for the testing of circuit boards	published
DTG International GmbH	Germany	20 2012 103 517.0	09/14/2012				presently being searched
atg Luther & Maelzer GmbH	Germany	199 43 388.7 - 09	10/9/1999	199 43 388		Vorrichtu ng zum Prüfen von Leiterplatt en	granted
atg test systems GmbH & Co. KG	Japan	2000-272879	8/9/2000	4 031 185		Vorrichtu ng zum Prüfen von Leiterplatt en	granted
atg test systems GmbH	Taiwan, R.O.C.	89118547	8/9/2000	156593		Printed Circuit Board Tester	granted
atg test systems GmbH & Co. KG	U.S.A.	09/656,088	6/9/2000	US 6,445,173 B1		Printed Circuit Board Tester	granted
DTG International GmbH	Europe	00 118 531.3 - 1236 (1 083 434)	08/25/2000			Vorrichtu ng zum Prüfen von Leiterplatt en	examinati on
atg test systems GmbH & Co. KG	Austria	aufgrund EP 01 974 129.7	7/8/2001	EP 1 315 975		Method and Device for Testing Printed Circuit Boards with a Parallel Tester	national phase (EP)
atg test systems GmbH & Co. KG	China	01814789.5	7/8/2001	ZL018147895		Method and Device for Testing Printed	granted

						Circuit Boards with a Parallel Tester	
atg Luther & Maelzer GmbH	Germany	501 09 393.1-08	7/8/2001	EP 1 315 975		Method and Device for Testing Printed Circuit Boards with a Parallel Tester	national phase (EP)
atg test systems GmbH & Co. KG	Europe	01 974 129.7 - 2216	7/8/2001	1 315 975		Method and Device for Testing Printed Circuit Boards with a Parallel Tester	granted
atg test systems GmbH & Co. KG	Great Britain	aufgrund EP 01 974 129.7	7/8/2001	EP 1 315 975		Method and Device for Testing Printed Circuit Boards with a Parallel Tester	national phase (EP)
atg test systems GmbH & Co. KG	Hong Kong	03108483.4	7/8/2001	HK1056219		Method and Device for Testing Printed Circuit Boards with a Parallel Tester	granted
atg test systems GmbH & Co. KG	Italy	027613BE/2006 aufgrund 1 315 975 (EP 01 974 129.7)	7/8/2001	EP 1 315 975		Method and Device for Testing Printed Circuit Boards with a Parallel Tester	national phase (EP)
atg test systems GmbH & Co. KG	Japan	2002-526164	7/8/2001	3,928,129		Method and Device for Testing Printed Circuit Boards with a Parallel Tester	granted
atg test systems GmbH	Korea	10-2003-7003291	5/3/2003	509340		Method and Device for Testing	granted

						Printed Circuit Boards with a Parallel Tester	
atg test systems GmbH & Co. KG	Singapore	200301056-8	7/8/2001	95297		Method and Device for Testing Printed Circuit Boards with a Parallel Tester	granted
atg test systems GmbH & Co. KG	China	18160336	09/28/2001	ZL 01816033.6		Module for a Testing Device for Testing Printed Circuit Boards	granted
atg Luther & Maelzer GmbH	Germany	501 06 269.6-08	09/28/2001	1 322 967 B1		Modul für eine Prüfvorrichtung zum Testen von Leiterplatten	national phase (EP)
atg test systems GmbH & Co. KG	Europe	01 983 514.9 - 1216	09/28/2001	1 322 967		Modul für eine Prüfvorrichtung zum Testen von Leiterplatten	granted
atg test systems GmbH & Co. KG	Great Britain	01 983 514.9-2216	09/28/2001	1 322 967		Modul für eine Prüfvorrichtung zum Testen von Leiterplatten	national phase (EP)
atg test systems GmbH & Co. KG	Hong Kong	03109204.0	09/28/2001	HK1059646		Module for a Testing Device for Testing Printed Circuit Boards	granted
atg test systems GmbH & Co. KG	Italy	28767BE/2005 aufgrund 01 983 514.9-2216	09/28/2001			Modul für eine Prüfvorrichtung zum Testen von Leiterplatten	national phase (EP)
atg test systems GmbH & Co. KG	Japan	2002-534850	09/28/2001	3,924,724		Module for a Testing Device for Testing	granted

						Printed Circuit Boards	
atg test systems GmbH	Korea	10-2003-7004645	09/28/2001	523300		Module for a Testing Device for Testing Printed Circuit Boards	granted
atg test systems GmbH & Co. KG	Singapore	200301797-7 aus PCT/EP01/11265	09/28/2001	95918		Module for a Testing Device for Testing Printed Circuit Boards	granted
atg test systems GmbH & Co. KG	Taiwan, R.O.C.	90124449	3/10/2001	I263059		Modul for a testing device for testing printed circuit boards	granted
atg Luther & Maelzer GmbH	Germany	101 60 119.0-35	7/12/2001			Prüfsonde für einen Fingertest er	published
atg test systems GmbH & Co. KG	Austria	E 305 613 aufgrund EP 02 792 764.9 - 2216	11/14/2002	1 451 594		Prüfsonde für einen Fingertest er und Fingertest er	national phase (EP)
atg test systems GmbH & Co. KG	China	02822468. X aus PCT/EP02/12770	11/14/2002	ZL 02822468.X		Test Probe for a Finger Tester and Finger Tester	granted
atg Luther & Maelzer GmbH	Germany	502 04 420.9 -08	11/14/2002	1 451 594		Prüfsonde für einen Fingertest er und Fingertest er	national phase (EP)
atg test systems GmbH & Co. KG	Europe	02 792 764.9-2216 (PCT/EP02/12770)	11/14/2002	1 451 594		Prüfsonde für einen Fingertest er	granted
atg test systems GmbH & Co. KG	France	02 792 764.9 - 2216	11/14/2002	1 451 594		Test probe for a finger tester and correspon ding finger tester	national phase (EP)
atg test systems GmbH & Co. KG	Finland	FI/EP 1 451 594	11/14/2002	1 451 594		Test Probe for a Finger Tester and correspon ding Finger	national phase (EP)

						Tester	
atg test systems GmbH & Co. KG	Great Britain	02 792 764.9 - 2216	11/14/2002	1 451 594		Test probe for a finger tester and correspon ding finger tester	national phase (EP)
atg test systems GmbH & Co. KG	Italy	034711BE/2005 aufgrund 02 792 764.9 - 2216	11/14/2002	1 451 594		Test probe for a finger tester and correspon ding finger tester	national phase (EP)
atg test systems GmbH & Co. KG	Japan	2003-549931	11/14/2002	4073024		Test Probe for a Finger Tester and correspon ding Finger Tester	granted
atg test systems GmbH & Co. KG	Korea	10-2004-7007869	11/14/2002	10-670115		Test Probe for a Finger Tester and Correspon ding Finger Tester	granted
atg test systems GmbH & Co. KG	Taiwan, R.O.C.	91133428	11/14/2002	I275802		Test Probe for a Finger Tester and Finger Tester	granted
atg Luther & Maelzer GmbH	U.S.A.	12/248,166	3/7/2004	RE 43,739		Test Probe for a Finger Tester and Correspon ding Finger Tester (Re-Issue)	examinati on
atg Luther & Maelzer GmbH	Germany	502 09 202.5-08	11/14/2002			Finger tester	national phase (EP)
atg test systems GmbH	Europe	1 542 023 (05 002 153.4 - 2213)	11/14/2002	1 542 023		Finger tester	granted
atg test systems GmbH	Finland	EP 1 542 023 (05 002 153.4)	11/14/2002			Finger tester	national phase (EP)
atg test systems GmbH	France	EP 1 542 023 (05 002 153.4)	11/14/2002			Finger tester	national phase (EP)

atg test systems GmbH	Great Britain	EP 1 542 023 (05 002 153.4)	11/14/2002			Finger tester	national phase (EP)
atg test systems GmbH	Italy	19068DE/2005 aufgrund EP 1 542 023 (05 002 153.4)	11/14/2002			Finger tester	national phase (EP)
atg test systems GmbH & Co. KG	Japan	2007-303001	11/14/2002	4780677		Test Probe for a Finger Tester and correspon ding Finger Tester	granted
atg test systems GmbH & Co. KG	U.S.A.	11/121,802	4/5/2005	7,190,182		Test Probe for Finger Tester and Correspon ding Finger Tester	granted
atg test systems GmbH & Co. KG	U.S.A.	11/466,663	08/23/2006	7,355,424		Test Probe for Finger Tester and Correspon ding Finger Tester	granted
atg Luther & Maelzer GmbH	Germany	102 20 343.1-09	7/5/2002	102 20 343		Vorrichtu ng und Verfahren zum Prüfen von Leiterplatt en, und Prüfsonde für diese Vorrichtu ng und dieses Verfahren	granted
atg test systems GmbH & Co. KG	China	03810114.9 aufgrund PCT/EP2003/044 68	04/29/2003	ZL 03 8 10114.9		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	granted
atg Luther & Maelzer GmbH	Germany	503 05 905.6-08	04/29/2003	1 502 123		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this	national phase (EP)

						Apparatus and this Method	
atg test systems GmbH	Europe	03 725 115.4 (1 502 123)	04/29/2003	1 502 123		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	granted
atg test systems GmbH	Finland	aufgrund EP 03 725 115.4 (1 502 123)	04/29/2003	1 502 123		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	national phase (EP)
atg test systems GmbH	France	aufgrund EP 03 725 115.4 (1 502 123)	04/29/2003	1 502 123		Device and Method for the Testing of Circuit Boards, and Test Probe for said Device and Method	national phase (EP)
atg test systems GmbH	Great Britain	aufgrund EP 03 725 115.4 (1 502 123)	04/29/2003	1 502 123		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	national phase (EP)
atg test systems GmbH	Italy	aufgrund EP 03 725 115.4 (1 502 123)	04/29/2003	1 502 123		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	national phase (EP)

atg test systems GmbH & Co. KG	Japan	2004-503977	04/29/2003	4245166		Device and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	granted
atg test systems GmbH & Co. KG	Korea	10-2004-7017748 - PCT/EP 03/04468	04/29/2003	747107		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	granted
atg test systems GmbH & Co. KG	Taiwan, R.O.C.	92112245	5/5/2003	I239405		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	granted
atg test systems GmbH & Co. KG	U.S.A.	10/981,079 aufgrund PCT/EP03/04468	04/29/2003	7,015,711		Apparatus and Method for the Testing of Circuit Boards, and Test Probe for this Apparatus and this Method	granted
atg test systems GmbH & Co. KG	China	200480007025.9 aus PCT/EP2004/002 420	9/3/2004	ZL 2004 8 0007025.9		Method of testing empty printed circuit boards	granted
DTG International GmbH	Germany	50 2004 011 042.8-08	9/3/2004			Method for testing empty printed circuit boards	national phase (EP)
DTG International GmbH	Europe	04 739 062.0-2216 aufgrund PCT/EP2004/002 420	9/3/2004	1 623 242		Method for testing empty printed circuit boards	granted

atg Luther & Maelzer GmbH	France	1 623 242 (04 739 062.0-2216)	9/3/2004			Method for testing empty printed circuit boards	national phase (EP)
DTG International GmbH	Great Britain	1 623 242 (04 739 062.0-2216)	9/3/2004			Method for testing empty printed circuit boards	national phase (EP)
DTG International GmbH	Italy	1 623 242 (04 739 062.0-2216)	9/3/2004	127037		Method for testing bare printed circuit boards	national phase (EP)
atg test systems GmbH & Co. KG	Japan	4,985,940	9/3/2004	4,985,940		Method of testing non-componen ted circuit boards	granted
atg test systems GmbH	Korea	10-2005-7021194 aufgrund PCT/EP2004/002 420	9/3/2004	782109		Method of testing non-componen ted circuit boards	granted
atg test systems GmbH & Co. KG	Taiwan, R.O.C.	93107836	03/23/2004	I245908		METHO D OF TESTING NON-COMPO NENTED CIRCUIT BOARDS	granted
atg test systems GmbH & Co. KG	U.S.A.	11/225,334 aufgrund PCT/EP2004/002 420	9/3/2004	7,250,782		Method for Testing Non-Compone nted Circuit Boards	granted
atg Luther & Maelzer GmbH	Germany	10 2005 028 191.5-09	06/17/2005	10 2005 028 191		Verfahren zum Testen von unbestück ten, großflächi gen Leiterplatt en mit einem Fingertest er	granted
DTG International GmbH	Austria	504846	05/31/2006			Verfahren zum Testen von unbestück ten, großflächi gen Leiterplatt en mit	national phase (EP)

						einem Fingertester	
DTG International GmbH	Switzerland	1 920 263 (06 754 013.8-2216)	05/31/2006			Verfahren zum Testen von unbestückten, großflächigen Leiterplatten mit einem Fingertester	national phase (EP)
atg Luther & Maelzer GmbH	China	200680021697.4	05/31/2006			Method of Testing Non-Componented Large Printed Circuit Boards Using a Finger Tester	examination
DTG International GmbH	Germany	50 2006 009 268.9-08	05/31/2006			Verfahren zum Testen von unbestückten, großflächigen Leiterplatten mit einem Fingertester	national phase (EP)
DTG International GmbH	Europe	06 754 013.8-2216	05/31/2006	1 920 263		Verfahren zum Testen von unbestückten, großflächigen Leiterplatten mit einem Fingertester	granted
DTG International GmbH	Great Britain	06 754 013.8-2216	05/31/2006	1 920 263		Verfahren zum Testen von unbestückten, großflächigen Leiterplatten mit einem Fingertester	national phase (EP)

DTG International GmbH	Italy	25607BE/2011	05/31/2006			Verfahren zum Testen von unbestückten, großflächigen Leiterplatten mit einem Fingertester	national phase (EP)
atg Luther & Maelzer GmbH	Japan	2008-516165	05/31/2006	4987862		Method of testing non-componented large printed circuit boards using a finger tester	granted
atg Luther & Maelzer GmbH	Korea	10 -2008-7001152	05/31/2006	10-1035244		Method of testing unloaded, large-area printed circuit boards with a finger tester	granted
DTG International GmbH	Niederlande	06 754 013.8-2216	05/31/2006	1 920 263		Verfahren zum Testen von unbestückten, großflächigen Leiterplatten mit einem Fingertester	national phase (EP)
atg test systems GmbH & Co. KG	Taiwan, R.O.C.	95116995	12/5/2006	I316139		Method for Testing Non-Componented Large Printed Circuit Boards Using a Finger Tester	granted
atg Luther & Maelzer GmbH	Germany	10 2006 005 800.3-09	8/2/2006	10 2006 005 800		Verfahren und Vorrichtung zum Testen von unbestückten Leiterplatten	granted

DTG International GmbH	Austria	07703071.6-2216	01/26/2007			Verfahren und Vorrichtung zum Testen von unbestückten Leiterplatten	national phase (EP)
DTG International GmbH	Switzerland	07703071.6-2216	01/26/2007			Verfahren und Vorrichtung zum Testen von unbestückten Leiterplatten	national phase (EP)
atg Luther & Maelzer GmbH	China	200780001486.9	01/26/2007	ZL 2007 8 0001486.9		Method and device for the testing of non-componented circuit boards	granted
DTG International GmbH	Germany	50 2007 008 761.0	01/26/2007			Verfahren und Vorrichtung zum Testen von unbestückten Leiterplatten	national phase (EP)
DTG International GmbH	Europe	1 982 203 (07703071.6-2216)	01/26/2007	1 982 203		Verfahren und Vorrichtung zum Testen von unbestückten Leiterplatten	granted
DTG International GmbH	Italy	31895BE/2011	01/26/2007			Verfahren und Vorrichtung zum Testen von unbestückten Leiterplatten	national phase (EP)
atg Luther & Maelzer GmbH	Korea	10-2008-7021909	01/26/2007	10-1154819		Method and device for the testing of non-componented circuit boards	granted
atg test systems GmbH	Taiwan, R.O.C.	96103078	01/26/2007			Method and Device for	examination

						the Testing of Non-Componented Circuit Boards	
atg Luther & Maelzer GmbH	U.S.A.	12/097,819	01/26/2007	7,821,278		Method and device for the testing of non-componented circuit boards	examination
atg Luther & Maelzer GmbH	Japan	2008-551730	01/26/2007			Method and device for the testing of non-componented circuit boards	examination request filed
atg Luther & Maelzer GmbH	Germany	10 2006 006 255.8-35	10/2/2006			Fingertester zum Prüfen von unbestückten Leiterplatten und Verfahren zum Prüfen unbestückter Leiterplatten mit einem Fingertester	published
atg Luther & Maelzer GmbH	Austria	1 982 197 (06818561.0-1524)	11/15/2006			Finger Tester for the Testing of Non-Componented Printed Circuit Boards and Method of Testing Non-Componented printed Circuit Boards with a Finger Tester	national phase (EP)
DTG International GmbH	Switzerland	1 982 197 (06818561.0-1524)	11/15/2006			Finger Tester for the Testing of Non-Componented	national phase (EP)

						Printed Circuit Boards and Method of Testing Non-Componented printed Circuit Boards with a Finger Tester	
atg Luther & Maelzer GmbH	China	200680045368.3	11/15/2006			Finger Tester for the Testing of Non-Componented Printed Circuit Boards and Method of Testing Non-Componented printed Circuit Boards with a Finger Tester	examination request filed
DTG International GmbH	Germany	1 982 197 (06818561.0-1524)	11/15/2006			Finger Tester for the Testing of Non-Componented Printed Circuit Boards and Method of Testing Non-Componented printed Circuit Boards with a Finger Tester	national phase (EP)
DTG International GmbH	Europe	06 818 561.0-1524	11/15/2006	1982197		Finger Tester for the Testing of Non-Componented Printed Circuit Boards and	granted

						Method of Testing Non-Componented printed Circuit Boards with a Finger Tester	
atg Luther & Maelzer GmbH	France	1 982 197 (06818561.0-1524)	11/15/2006			Finger Tester for the Testing of Non-Componented Printed Circuit Boards and Method of Testing Non-Componented printed Circuit Boards with a Finger Tester	national phase (EP)
atg Luther & Maelzer GmbH	Hong Kong	09110535.2	11/15/2006			Finger Tester for the Testing of Non-Componented Printed Circuit Boards and Method of Testing Non-Componented printed Circuit Boards with a Finger Tester	published
DTG International GmbH	Italy	1 982 197 (06818561.0-1524)	11/15/2006			Finger Tester for the Testing of Non-Componented Printed Circuit Boards and Method of Testing Non-Compone	national phase (EP)

						nted printed Circuit Boards with a Finger Tester	
atg Luther & Maelzer GmbH	Japan	2008-551658	11/15/2006			Finger Tester for the Testing of Non-Compone nted Printed Circuit Boards and Method of Testing Non-Compone nted printed Circuit Boards with a Finger Tester	examinati on request filed
atg Luther & Maelzer GmbH	Korea	10-2008-7021981	11/15/2006	10-1005197		Finger Tester for the Testing of Non-Compone nted Printed Circuit Boards and Method of Testing Non-Compone nted printed Circuit Boards with a Finger Tester	granted
atg test systems GmbH	Taiwan, R.O.C.	95149348	12/27/2006	I356168		Finger Tester for the Testing of Non-Compone nted Printed Circuit Boards and Method of Testing Non-Compone nted Printed Circuit Boards	granted

						with a Finger Tester	
atg Luther & Maelzer GmbH	U.S.A.	12/097,824	11/15/2006	7,859,281		Finger Tester for the Testing of Non-Componented Printed Circuit Boards and Method of Testing Non-Componented printed Circuit Boards with a Finger Tester	granted
DTG International GmbH	Austria	08804890.5-2216	09/29/2008			Full Raster Cartridge for a Parallel Tester for Testing an Unpopulated Printed Circuit Board, Spring Contact Pin for such a Full Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	national phase (EP)
DTG International GmbH	Switzerland	08804890.5-2216	09/29/2008			Full Raster Cartridge for a Parallel Tester for Testing an Unpopulated Printed Circuit Board, Spring Contact Pin for such a Full	national phase (EP)

						Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	
atg Luther & Maelzer GmbH	China	200880110211.3	09/29/2008			Full Raster Cartridge for a Parallel Tester for Testing an Unpopulated Printed Circuit Board, Spring Contact Pin for such a Full Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	examination
DTG International GmbH	Germany	50 2008 007 616.6	09/29/2008			Full Raster Cartridge for a Parallel Tester for Testing an Unpopulated Printed Circuit Board, Spring Contact Pin for such a Full Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	national phase (EP)
DTG International GmbH	Europe	08804890.5-2216	09/29/2008	2210115		Full Raster Cartridge for a Parallel Tester for Testing an Unpopulat	granted

						ed Printed Circuit Board, Spring Contact Pin for such a Full Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	
DTG International GmbH	Great Britain	08804890.5-2216	09/29/2008			Full Raster Cartridge for a Parallel Tester for Testing an Unpopulated Printed Circuit Board, Spring Contact Pin for such a Full Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	national phase (EP)
atg Luther & Maelzer GmbH	Hong Kong	11102307.1	8/3/2011			Full Raster Cartridge for a Parallel Tester for Testing an Unpopulated Printed Circuit Board, Spring Contact Pin for such a Full Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	filed

DTG International GmbH	Italy	28186BE/2012	09/29/2008			Full Raster Cartridge for a Parallel Tester for Testing an Unpopulated Printed Circuit Board, Spring Contact Pin for such a Full Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	national phase (EP)
atg Luther & Maelzer GmbH	Korea	10-2010-7009711	09/29/2008			Full Raster Cartridge for a Parallel Tester for Testing an Unpopulated Printed Circuit Board, Spring Contact Pin for such a Full Raster Cartridge and Adapter for Testing an Unpopulated Printed Circuit Board	examination
atg Luther & Maelzer GmbH	Taiwan, R.O.C.	97137771	1/10/2008			Full grid cassette for a parallel tester for testing a non-componented printed circuit board, spring contact pin for such a full grid cassette	published

						and adapter for a parallel tester for testing a non-componen ted printed circuit board	
DTG International GmbH	U.S.A.	12/681,295	09/29/2008			Full grid cassette for a parallel tester for testing a non-componen ted printed circuit board, spring contact pin for such a full grid cassette and adapter for a parallel tester for testing a non-componen ted printed circuit board	published
atg Luther & Maelzer GmbH	Germany	10 2008 006 130.1-35	01/25/2008			Modul für einen Paralleltes ter zum Prüfen von Leiterplatt en	examinati on
DTG International GmbH	Austria	09704390.5-2216	01/19/2009			Modul für einen Paralleltes ter zum Prüfen von Leiterplatt en	national phase (EP)
DTG International GmbH	Switzerland	09704390.5-2216	01/19/2009			Modul für einen Paralleltes ter zum Prüfen von Leiterplatt en	national phase (EP)
DTG International GmbH	China	200980102922.0	01/19/2009			Module for a parallel tester for	examinati on request filed

						testing of circuit boards	
DTG International GmbH	Germany	50 2009 004 001.6	01/19/2009			Modul für einen Paralleltes ter zum Prüfen von Leiterplatt en	national phase (EP)
DTG International GmbH	Europe	09704390.5-2216	01/19/2009	2238461		Modul für einen Paralleltes ter zum Prüfen von Leiterplatt en	granted
DTG International GmbH	Great Britain	09704390.5-2216	01/19/2009			Modul für einen Paralleltes ter zum Prüfen von Leiterplatt en	national phase (EP)
DTG International GmbH	Hong Kong	11106078.9	01/19/2009			Module for a parallel tester for testing of circuit boards	filed
atg Luther & Maelzer GmbH	India	1504/MUMNP/2 010	01/19/2009			Module for a parallel tester for testing of circuit boards	examinati on request filed
DTG International GmbH	Italy	09704390.5-2216	01/19/2009			Modul für einen Paralleltes ter zum Prüfen von Leiterplatt en	national phase (EP)
DTG International GmbH	Japan	2010-543471	01/19/2009			Module for a parallel tester for testing of circuit boards	examinati on request filed
DTG International GmbH	Korea	10-2010-7018652	01/19/2009	10-1207957		Module for a parallel tester for testing of circuit boards	examinati on request filed
DTG International GmbH	Singapore	201005017-7	01/19/2009	163116		Module for a parallel tester for testing of circuit	granted

						boards	
atg Luther & Maelzer GmbH	Taiwan, R.O.C.	98102317	01/21/2009			Module for a parallel tester for the testing of circuit boards	filed
DTG International GmbH	U.S.A.	12/863,739	01/19/2009	7982481	07/19/2011	Module for a parallel tester for testing of circuit boards	granted
DTG International GmbH	Austria	A 1620/2008	10/15/2008	507,468		Ermittlun g von Eigenscha ften einer elektrisch en Vorrichtu ng	granted
DTG International GmbH	China	200980141259.5	10/14/2009			Determina tion of Properties of an Electrical Device	examinati on request filed
DTG International GmbH	Europe	09751834.4-2216	10/14/2009			Determina tion of Properties of an Electrical Device	examinati on
DTG International GmbH	Japan	2011-531477	10/14/2009			Determina tion of Properties of an Electrical Device	examinati on
DTG International GmbH	Korea	10-2011-7009645	10/14/2009			Determina tion of Properties of an Electrical Device	filed
DTG International GmbH	Taiwan, R.O.C.	98134657	10/13/2009			Determina tion of Properties of an Electrical Device	examinati on
DTG International GmbH	U.S.A.	13/124,454	10/14/2009			Determina tion of Properties of an Electrical Device	published
atg Luther & Maelzer GmbH	Germany	10 2009 004 555.4-35	01/14/2009			Verfahren zum Prüfen von Leiterplatt en	examinati on

DTG International GmbH	Brasil	PI1007227-6	01/13/2010			Method for the Testing of Circuit Boards	filed
DTG International GmbH	China	201080004643.3	01/14/2009			Method for the Testing of Circuit Boards	examination request filed
DTG International GmbH	Europe	10700178.6-2216	01/13/2010			Method for the Testing of Circuit Boards	examination
DTG International GmbH	Hong Kong	11111504.3	01/13/2010			Method for Testing Printed Circuit Boards	filed
DTG International GmbH	Japan	2011-545728	01/13/2010			Method for the Testing of Circuit Boards	filed
DTG International GmbH	Korea	10-2011-7018558	01/13/2010			Method for the Testing of Circuit Boards	filed
DTG International GmbH	Singapore	201105072-1	01/13/2010			Method for the Testing of Circuit Boards	filed
DTG International GmbH	Taiwan, R.O.C.	99100968	01/14/2010			Method for the Testing of Circuit Boards	examination request filed
DTG International GmbH	U.S.A.	13/143,697	01/13/2010			Method for the Testing of Circuit Boards	published
atg Luther & Maelzer GmbH	Germany	10 2009 016 181.3-35	3/4/2009			Kontaktierungseinheit für eine Testvorrichtung zum Testen von Leiterplatten	examination request filed
DTG International GmbH	Brasil	PI1014042-5	1/4/2010			Contact-Connection Unit for a Test Apparatus for Testing Printed Circuit Boards	filed
DTG International GmbH	China	201080015767.1	1/4/2010			Contact-Connection Unit for	examination request filed

						a Test Apparatus for Testing Printed Circuit Boards	
DTG International GmbH	Europe	10716503-7-2216	1/4/2010			Contact-Connection Unit for a Test Apparatus for Testing Printed Circuit Boards	examination
DTG International GmbH	Hong Kong	12103986.6	1/4/2010			Contact-Connection Unit for a Test Apparatus for Testing Printed Circuit Boards	filed
DTG International GmbH	Japan	2012-502691	1/4/2010			Contact-Connection Unit for a Test Apparatus for Testing Printed Circuit Boards	filed
DTG International GmbH	Korea	10-2011-70261	1/4/2010			Contact-Connection Unit for a Test Apparatus for Testing Printed Circuit Boards	filed
DTG International GmbH	Taiwan, R.O.C.	99110193	1/4/2010			Contacting Unit for a Test Apparatus for Testing Printed Circuit Boards	examination request filed
DTG International GmbH	U.S.A.	13/262,625	1/4/2010			Contact-Connection Unit for a Test Apparatus for Testing Printed Circuit Boards	published

Multitest elektronische Systeme GmbH	Germany	DE102013203536	3/1/2013			Vorrichtung zum Prüfen von elektronischen Bauteilen	filed, in examination
Multitest elektronische Systeme GmbH	Europe	EP13155976	2/20/2013			Apparatus and method for testing electronic devices	filed, in examination
Multitest elektronische Systeme GmbH	US	US13/772,178	2/20/2013			Apparatus and method for testing electronic devices	filed, in examination
Multitest elektronische Systeme GmbH	Europe	EP13157620	3/4/2013			Verfahren und Vorrichtung zum Prüfen von elektronischen Bauteilen	filed, in examination
Multitest elektronische Systeme GmbH	Europe	EP12189810	10/24/2012			Kontaktfeder für einen Prüfsockel für die Hochstrom-Prüfung eines elektronischen Bauteils	filed, in examination
Multitest elektronische Systeme GmbH	Europe	EP12171824	6/18/2012			Vorrichtung zum Prüfen von elektronischen Bauteileelementen	filed, in examination
Multitest elektronische Systeme GmbH	China	CN201310197184.0	5/24/2013			Device for testing electronic component devices	filed, in examination
Multitest elektronische Systeme GmbH	Japan	JP2013-106676	5/21/2013			Device for testing electronic component devices	filed, in examination
Multitest elektronische Systeme GmbH	Korea, South	KR10-2013-0063595	6/3/2013			Device for testing electronic component devices	filed, in examination
Multitest elektronische Systeme GmbH	Malaysia	PI2013003055	6/18/2013			Device for testing electronic component devices	filed, in examination

Multitest elektronische Systeme GmbH	Philippines	PH1-2013-000170	6/13/2013			Device for testing electronic component devices	filed, in examination
Multitest elektronische Systeme GmbH	Singapore	still waiting for notification	6/13/2013			Device for testing electronic component devices	filed, in examination
Multitest elektronische Systeme GmbH	Taiwan	TW102120994	6/14/2013			Device for testing electronic component devices	filed, in examination
Multitest elektronische Systeme GmbH	US	US13/917,482	6/13/2013			Device for testing electronic component devices	filed, in examination
Multitest elektronische Systeme GmbH	Europe	EP12171997	6/14/2012			Vorrichtung und Verfahren zum Prüfen von elektronischen Bauteilelementen auf einem Träger oder einem Substrat	filed, in examination
Multitest elektronische Systeme GmbH	China	CN201310196875.9	5/24/2013			Device and method for testing electronic component devices on a carrier or a substrate	filed, in examination
Multitest elektronische Systeme GmbH	Japan	JP2013-108480	5/23/2013			Device and method for testing electronic component devices on a carrier or a substrate	filed, in examination
Multitest elektronische Systeme GmbH	Korea, South	KR10-2013-0064948	6/5/2013			Device and method for testing electronic component devices on a carrier or a substrate	filed, in examination
Multitest elektronische Systeme GmbH	Malaysia	PI2013002058	6/5/2013			Device and method for testing	filed, in examination

						electronic componen t devices on a carrier or a substrate	
Multitest elektronische Systeme GmbH	Philippines	PH1-2013-000165	6/10/2013			Device and method for testing electronic componen t devices on a carrier or a substrate	filed, in examinati on
Multitest elektronische Systeme GmbH	Singapore	SG201304466-4	6/10/2013			Device and method for testing electronic componen t devices on a carrier or a substrate	filed, in examinati on
Multitest elektronische Systeme GmbH	Thailand	TH1301002936	5/31/2013			Device and method for testing electronic componen t devices on a carrier or a substrate	filed, in examinati on
Multitest elektronische Systeme GmbH	Taiwan	TW102119679	6/4/2013			Device and method for testing electronic componen t devices on a carrier or a substrate	filed, in examinati on
Multitest elektronische Systeme GmbH	US	US13/914,590	6/10/2013			Device and method for testing electronic componen t devices on a carrier or a substrate	filed, in examinati on
Multitest elektronische Systeme GmbH	Europe	EP12171824	6/13/2012			Vorrichtu ng und Verfahren zum Entnehme n von geprüften Halbleiter elementen	filed, in examinati on
Multitest elektronische Systeme GmbH	China	CN20131019716 3.9	5/24/2013			Device and method for	filed, in examinati on

						removing tested semicond uctor componen ts	
Multitest elektronische Systeme GmbH	Japan	JP2013-107834	5/22/2013			Device and method for removing tested semicond uctor componen ts	filed, in examinati on
Multitest elektronische Systeme GmbH	Korea, South	KR10-2013-0063051	5/31/2013			Device and method for removing tested semicond uctor componen ts	filed, in examinati on
Multitest elektronische Systeme GmbH	Malaysia	PI2013002059	6/5/2013			Device and method for removing tested semicond uctor componen ts	filed, in examinati on
Multitest elektronische Systeme GmbH	Philippines	PH1-2013-000166	6/10/2013			Device and method for removing tested semicond uctor componen ts	filed, in examinati on
Multitest elektronische Systeme GmbH	Singapore	SG201304468-0	6/10/2013			Device and method for removing tested semicond uctor componen ts	filed, in examinati on
Multitest elektronische Systeme GmbH	Thailand	TH1301002937	5/31/2013			Device and method for removing tested semicond uctor componen ts	filed, in examinati on

Multitest elektronische Systeme GmbH	Taiwan	TW102120020	6/6/2013			Device and method for removing tested semicond uctor componen ts	filed, in examinati on
Multitest elektronische Systeme GmbH	US	US13/914,603	6/10/2013			Device and method for removing tested semicond uctor componen ts	filed, in examinati on
Multitest elektronische Systeme GmbH	Europe	EP12170883	6/5/2012			Test device, test system, method and carrier for testing electonic componen ts under variable pressure conditions	filed, in examinati on
Multitest elektronische Systeme GmbH	China	CN201310197078.2	5/24/2013			Test device, test system, method and carrier for testing electonic componen ts under variable pressure conditions	filed, in examinati on
Multitest elektronische Systeme GmbH	Japan	JP2013-107625	5/22/2013			Test device, test system, method and carrier for testing electonic componen ts under variable pressure conditions	filed, in examinati on
Multitest elektronische Systeme GmbH	Korea, South	KR10-2013-0059103	5/24/2013			Test device, test system, method and carrier for testing	filed, in examinati on

						electonic componen ts under variable pressure conditions	
Multitest elektronische Systeme GmbH	Malaysia	PI2013001820	5/17/2013			Test device, test system, method and carrier for testing electonic componen ts under variable pressure conditions	filed, in examinati on
Multitest elektronische Systeme GmbH	Philippines	PH1-2013-000137	5/23/2013			Test device, test system, method and carrier for testing electonic componen ts under variable pressure conditions	filed, in examinati on
Multitest elektronische Systeme GmbH	Singapore	SG201303804-7	5/16/2013			Test device, test system, method and carrier for testing electonic componen ts under variable pressure conditions	filed, in examinati on
Multitest elektronische Systeme GmbH	Thailand	TH1301002810	5/28/2013			Test device, test system, method and carrier for testing electonic componen ts under variable pressure conditions	filed, in examinati on
Multitest elektronische Systeme GmbH	Taiwan	TW102119243	5/31/2013			Test device, test system, method and carrier for testing	filed, in examinati on

						electonic components under variable pressure conditions	
Multitest elektronische Systeme GmbH	US	US13/905,010	5/29/2013			Test device, test system, method and carrier for testing electonic components under variable pressure conditions	filed, in examination
Multitest elektronische Systeme GmbH	US	US12/859,059	8/18/2010			System for post-processing of electronic components	decision to grant patent
Multitest elektronische Systeme GmbH	Malaysia	PI2010003595	7/29/2010			System for post-processing of electronic components	filed, in examination
Multitest elektronische Systeme GmbH	Japan	JP2010181849	8/16/2010			System for post-processing of electronic components	filed, in examination
Multitest elektronische Systeme GmbH	Korea, South	KR1020100080033	8/18/2010	KR101156743	7/3/2012	System for post-processing of electronic components	patented
Multitest elektronische Systeme GmbH	Philippines	PH12010000243	8/12/2010			System for post-processing of electronic components	filed, in examination
Multitest elektronische Systeme GmbH	China	CN201010257518	8/17/2010	CN101996913	5/8/2013	System for post-processing of electronic components	patented
Multitest elektronische Systeme GmbH	Europe	EP10171344	7/29/2010	EP2302399	10/10/2012	System for post-processing of electronic components	patented

Multitest elektronische Systeme GmbH	Germany (EP)	EP10171344	7/29/2010	602010003131	10/10/2012	System for post-processing of electronic components	validated (EP-patent EP2302399)
Multitest elektronische Systeme GmbH	Malta (EP)	EP10171344	7/29/2010	EP00908/2302399	10/10/2012	System for post-processing of electronic components	validated (EP-patent EP2302399)
Multitest elektronische Systeme GmbH	Italy (EP)	EP10171344	7/29/2010	31063BE/2012	10/10/2012	System for post-processing of electronic components	validated (EP-patent EP2302399)
Multitest elektronische Systeme GmbH	France (EP)	EP10171344	7/29/2010	2302399	10/10/2012	System for post-processing of electronic components	validated (EP-patent EP2302399)
Multitest elektronische Systeme GmbH	Austria (EP)	EP10171344	7/29/2010	579188	10/10/2012	System for post-processing of electronic components	validated (EP-patent EP2302399)
Multitest elektronische Systeme GmbH	Netherlands (EP)	EP10171344	7/29/2010	2302399	10/10/2012	System for post-processing of electronic components	validated (EP-patent EP2302399)
Multitest elektronische Systeme GmbH	UK (EP)	EP10171344	7/29/2010	2302399	10/10/2012	System for post-processing of electronic components	validated (EP-patent EP2302399)
Multitest elektronische Systeme GmbH	Finland (EP)	EP10171344	7/29/2010	2302399	10/10/2012	System for post-processing of electronic components	validated (EP-patent EP2302399)
Multitest elektronische Systeme GmbH	US	US859106	8/18/2010	US8230587	7/31/2012	Carrier for aligning electronic components with slidably arranged plates	patented
Multitest elektronische Systeme GmbH	Malaysia	PI2010003561	10/28/2010			Carrier for aligning electronic components with	filed, in examination

						slidably arranged plates	
Multitest elektronische Systeme GmbH	Japan	JP2010181848	8/16/2010	JP5148666	12/7/2012	Carrier for aligning electronic componen ts with slidably arranged plates	patented
Multitest elektronische Systeme GmbH	Korea, South	KR10201000800 31	8/18/2010	KR101191988	10/10/2012	Carrier for aligning electronic componen ts with slidably arranged plates	patented
Multitest elektronische Systeme GmbH	Philippines	PH12010000245	8/12/2010			Carrier for aligning electronic componen ts with slidably arranged plates	filed, in examinati on
Multitest elektronische Systeme GmbH	China	CN20101025717 6	8/17/2010			Carrier for aligning electronic componen ts with slidably arranged plates	filed, in examinati on
Multitest elektronische Systeme GmbH	Europe	EP10171337	7/29/2010	EP2290375	10/3/2012	Carrier for aligning electronic componen ts with slidably arranged plates	patented
Multitest elektronische Systeme GmbH	Germany (EP)	EP10171337	7/29/2010	60201000003041	10/3/2012	Carrier for aligning electronic componen ts with slidably arranged plates	validated (EP-patent EP229037 5)
Multitest elektronische Systeme GmbH	Malta (EP)	EP10171337	7/29/2010	EP00904/2290375	10/3/2012	Carrier for aligning electronic componen ts with slidably arranged plates	validated (EP-patent EP229037 5)
Multitest elektronische Systeme GmbH	Italy (EP)	EP10171337	7/29/2010	32168BE/2012	10/3/2012	Carrier for aligning electronic componen ts with slidably arranged plates	validated (EP-patent EP229037 5)

Multitest elektronische Systeme GmbH	France (EP)	EP10171337	7/29/2010	2290375	10/3/2012	Carrier for aligning electronic components with slidably arranged plates	validated (EP-patent EP2290375)
Multitest elektronische Systeme GmbH	US	US858400	8/17/2010			Two abutting sections of an align fixture together floatingly engaging an electronic component	filed, in examination
Multitest elektronische Systeme GmbH	Malaysia	PI2010003562	7/28/2010			Two abutting sections of an align fixture together floatingly engaging an electronic component	filed, in examination
Multitest elektronische Systeme GmbH	Japan	JP2010181847	8/16/2010			Two abutting sections of an align fixture together floatingly engaging an electronic component	filed, in examination
Multitest elektronische Systeme GmbH	Korea, South	KR102010000800 30	8/18/2010	KR101156725	6/14/2012	Two abutting sections of an align fixture together floatingly engaging an electronic component	patented
Multitest elektronische Systeme GmbH	Philippines	PH12010000242	8/12/2010			Two abutting sections of an align fixture together floatingly engaging an	filed, in examination

						electronic componen t	
Multitest elektronische Systeme GmbH	China	CN20101025763 8	8/17/2010			Two abutting sections of an align fixture together floatingly engaging an electronic componen t	filed, in examinati on
Multitest elektronische Systeme GmbH	Europe	EP10171341	7/29/2010	EP2290377	10/10/2012	Two abutting sections of an align fixture together floatingly engaging an electronic componen t	patented
Multitest elektronische Systeme GmbH	Germany (EP)	EP10171341	7/29/2010	602010003129	10/10/2012	Two abutting sections of an align fixture together floatingly engaging an electronic componen t	validated (EP-patent EP229037 7)
Multitest elektronische Systeme GmbH	Malta (EP)	EP10171341	7/29/2010	EP00906/2290377	10/10/2012	Two abutting sections of an align fixture together floatingly engaging an electronic componen t	validated (EP-patent EP229037 7)
Multitest elektronische Systeme GmbH	Italy (EP)	EP10171341	7/29/2010	30971BE/2012	10/10/2012	Two abutting sections of an align fixture together floatingly engaging an electronic componen t	validated (EP-patent EP229037 7)

Multitest elektronische Systeme GmbH	France (EP)	EP10171341	7/29/2010	2290377	10/10/2012	Two abutting sections of an align fixture together floatingly engaging an electronic componen t	validated (EP-patent EP229037 7)
Multitest elektronische Systeme GmbH	US	US858406	8/17/2010			An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	decision to grant patent
Multitest elektronische Systeme GmbH	Malaysia	PI2010003563	7/28/2010			An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	filed, in examinati on
Multitest elektronische Systeme GmbH	Japan	JP2010181846	8/16/2010	JP4910112	1/27/2012	An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	patented
Multitest elektronische Systeme GmbH	Korea, South	KR10201000800 29	8/18/2010	KR101156717	6/14/2012	An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	patented

Multitest elektronische Systeme GmbH	Philippines	PH12010000247	8/12/2010			An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	filed, in examinati on
Multitest elektronische Systeme GmbH	China	CN201010257640	8/17/2010			An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	filed, in examinati on
Multitest elektronische Systeme GmbH	Europe	EP10171343	7/29/2010	EP2290378	10/10/2012	An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	patented
Multitest elektronische Systeme GmbH	Germany (EP)	EP10171343	7/29/2010	602010003130	10/10/2012	An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	validated (EP-patent EP2290378)
Multitest elektronische Systeme GmbH	Malta (EP)	EP10171343	7/29/2010	EP00907/2290378	10/10/2012	An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	validated (EP-patent EP2290378)

Multitest elektronische Systeme GmbH	Italy (EP)	EP10171343	7/29/2010	31061BE/2012	10/10/2012	An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	validated (EP-patent EP2290378)
Multitest elektronische Systeme GmbH	France (EP)	EP10171343	7/29/2010	2290378	10/10/2012	An elastic unit as a separate elastic member to be mounted at an elastic unit receiving section of an align fixture	validated (EP-patent EP2290378)
Multitest elektronische Systeme GmbH	US	12/858383	8/17/2010	20110043982 A1	02/24/2011	An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	filed, in examination
Multitest elektronische Systeme GmbH	Malaysia	PI2010003564	7/28/2010			An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	filed, in examination
Multitest elektronische Systeme GmbH	Japan	JP2010181845	8/16/2010			An elastic unit for clamping an electronic component and extending below an electronic component receiving	filed, in examination

						volume of an align fixture	
Multitest elektronische Systeme GmbH	Korea, South	KR102010008002 8	8/18/2010	KR101194423	10/18/2012	An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	patented
Multitest elektronische Systeme GmbH	Philippines	PH12010000244	8/12/2010			An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	filed, in examination
Multitest elektronische Systeme GmbH	China	CN201010257544	8/17/2010			An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	filed, in examination
Multitest elektronische Systeme GmbH	Europe	EP10171340	7/29/2010	EP2290376	10/3/2012	An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	patented
Multitest elektronische Systeme GmbH	Germany (EP)	EP10171340	7/29/2010	602010003042	10/3/2012	An elastic unit for clamping an electronic	validated (EP-patent EP229037 6)

						component and extending below an electronic component receiving volume of an align fixture	
Multitest elektronische Systeme GmbH	Malta (EP)	EP10171340	7/29/2010	EP00905/2290376	10/3/2012	An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	validated (EP-patent EP229037 6)
Multitest elektronische Systeme GmbH	Italy (EP)	EP10171340	7/29/2010	31062BE/2012	10/3/2012	An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	validated (EP-patent EP229037 6)
Multitest elektronische Systeme GmbH	France (EP)	EP10171340	7/29/2010	2290376	10/3/2012	An elastic unit for clamping an electronic component and extending below an electronic component receiving volume of an align fixture	validated (EP-patent EP229037 6)
Multitest elektronische Systeme GmbH	US	US858394	8/17/2010	US8281483	10/9/2012	Elastic unit exerting two angled force components on an abutting section of an align fixture	patented

Multitest elektronische Systeme GmbH	Malaysia	PI2010003565	7/28/2010			Elastic unit exerting two angled force components on an abutting section of an align fixture	filed, in examination
Multitest elektronische Systeme GmbH	Japan	JP2010181844	8/16/2010	JP5148665	12/7/2012	Elastic unit exerting two angled force components on an abutting section of an align fixture	patented
Multitest elektronische Systeme GmbH	Korea, South	KR10201000800 27	8/18/2010	KR101156702	6/14/2012	Elastic unit exerting two angled force components on an abutting section of an align fixture	patented
Multitest elektronische Systeme GmbH	Philippines	PH12010000246	8/12/2010			Elastic unit exerting two angled force components on an abutting section of an align fixture	filed, in examination
Multitest elektronische Systeme GmbH	China	CN20101025762 4	8/17/2010			Elastic unit exerting two angled force components on an abutting section of an align fixture	filed, in examination
Multitest elektronische Systeme GmbH	Europe	EP10171333	7/29/2010	EP2290374	10/3/2012	Elastic unit exerting two angled force components on an abutting section of	patented

						an align fixture	
Multitest elektronische Systeme GmbH	Germany (EP)	EP10171333	7/29/2010	602010003040	10/3/2012	Elastic unit exerting two angled force components on an abutting section of an align fixture	validated (EP-patent EP2290374)
Multitest elektronische Systeme GmbH	Malta (EP)	EP10171333	7/29/2010	EP00903/2290374	10/3/2012	Elastic unit exerting two angled force components on an abutting section of an align fixture	validated (EP-patent EP2290374)
Multitest elektronische Systeme GmbH	Italy (EP)	EP10171333	7/29/2010	30970BE/2012	10/3/2012	Elastic unit exerting two angled force components on an abutting section of an align fixture	validated (EP-patent EP2290374)
Multitest elektronische Systeme GmbH	France (EP)	EP10171333	7/29/2010	2290374	10/3/2012	Elastic unit exerting two angled force components on an abutting section of an align fixture	validated (EP-patent EP2290374)
Multitest elektronische Systeme GmbH	Germany	DE102008029129	6/19/2008	DE102008029129	4/29/2010	Kontaktiervorrichtung und Verfahren zum Reinigen von Kontaktfedern	patented
Multitest elektronische Systeme GmbH	Germany	DE200810028034	6/12/2008			Kontaktsockel	filed, in examination

Multitest elektronische Systeme GmbH	US	US742888	6/12/2009	US8282428	10/9/2012	Contact base	patented
Multitest elektronische Systeme GmbH	Malaysia	PI2010002195	6/12/2009			Contact base	filed, in examination
Multitest elektronische Systeme GmbH	Singapore	SG201003408	6/12/2009	SG1615555	11/30/2012	Contact base	patented
Multitest elektronische Systeme GmbH	China	CN200980101187	6/12/2009			Contact base	filed, in examination
Multitest elektronische Systeme GmbH	Germany	DE200810020558	4/24/2008	DE102008020558	7/1/2010	Plunger mit Rückzentrierung	patented
Multitest elektronische Systeme GmbH	Germany	DE102008020585	4/24/2008	DE102008020585	3/24/2011	Plunger mit Schnellverriegelungssystem	patented
Multitest elektronische Systeme GmbH	US	US743792	4/9/2009	8476916	07/02/2013	Plunger with quick locking system	filed, in examination
Multitest elektronische Systeme GmbH	Malaysia	PI2010009194	4/9/2009			Plunger with quick locking system	filed, in examination
Multitest elektronische Systeme GmbH	Japan	JP2010535410	4/9/2009	JP5281651	5/31/2013	Plunger with quick locking system	patented
Multitest elektronische Systeme GmbH	Korea, South	KR1020107012054	4/9/2009	KR101141306	5/4/2012	Plunger with quick locking system	patented
Multitest elektronische Systeme GmbH	Philippines	PH12010501058	4/9/2009			Plunger with quick locking system	filed, in examination
Multitest elektronische Systeme GmbH	China	CN200980101186	4/9/2009			Plunger with quick locking system	filed, in examination
Multitest elektronische Systeme GmbH	Europe	EP09734358	4/9/2009	EP2193382	3/23/2011	Plunger with quick locking system	patented
Multitest elektronische Systeme GmbH	Germany (EP)	EP09734358	4/9/2009		3/23/2011	Plunger with quick locking system	validated (EP-patent EP2193382)

Multitest elektronische Systeme GmbH	Malta (EP)	EP09734358	4/9/2009	EP00302/2193382	3/23/2011	Plunger with quick locking system	validated (EP-patent EP219338 2)
Multitest elektronische Systeme GmbH	France (EP)	EP09734358	4/9/2009	2193382	3/23/2011	Plunger with quick locking system	validated (EP-patent EP219338 2)
Multitest elektronische Systeme GmbH	Germany	DE102008015916	3/27/2008	DE102008015916	2/10/2011	Verfahren und Vorrichtung zum Testen und Kalibrieren von elektronischen Halbleiterbauelementen, die Schall in elektrische Signale umwandeln	patented
Multitest elektronische Systeme GmbH	US	US810716	3/12/2009			Method and device for testing and calibrating electronic semiconductor components which convert sound into electrical signals	filed, in examination
Multitest elektronische Systeme GmbH	US Divisional application	US887429	9/21/2010			Device and method for aligning and holding a plurality of singulated semiconductor components in receiving pockets of a terminal carrier	filed, in examination
Multitest elektronische Systeme GmbH	Germany Divisional application	DE112009000200	2/12/2009	DE112009000200	1/14/2013	Vorrichtung und Verfahren zum Ausrichten und Halten einer	patented

						Mehrzahl singulierte r Halbleiter baueleme nte in Aufnahme taschen eines Klemmträ gers	
Multitest elektronische Systeme GmbH	Malaysia Divisional application	PI2010003836	2/12/2009			Device and method for aligning and holding a plurality of singulated semicond uctor componen ts in receiving pockets of a terminal carrier	filed, in examinati on
Multitest elektronische Systeme GmbH	Germany Utility Model	DE10200901872 6	12.02.009	DE202009018726 Utility Model	11/27/2012	Vorrichtu ng und Verfahren zum Ausrichte n und Halten einer Mehrzahl singulierte r Halbleiter baueleme nte in Aufnahme taschen eines Klemmträ gers	registered
Multitest elektronische Systeme GmbH	US	US665531	2/12/2009			Device and method for aligning and holding a plurality of singulated semicond uctor componen ts in receiving pockets of a terminal carrier	filed, in examinati on

Multitest elektronische Systeme GmbH	Malaysia	PI20094544	2/12/2009			Device and method for aligning and holding a plurality of singulated semicond uctor componen ts in receiving pockets of a terminal carrier	filed, in examinati on
Multitest elektronische Systeme GmbH	Japan	JP2010512720	2/12/2009	JP5291097	6/14/2013	Device and method for aligning and holding a plurality of singulated semicond uctor componen ts in receiving pockets of a terminal carrier	patented
Multitest elektronische Systeme GmbH	Korea, South	KR10200970245 13	2/12/2009	KR101097954	12/16/2011	Device and method for aligning and holding a plurality of singulated semicond uctor componen ts in receiving pockets of a terminal carrier	patented
Multitest elektronische Systeme GmbH	Philippines	PH12009502078	2/12/2009			Device and method for aligning and holding a plurality of singulated semicond uctor componen ts in receiving pockets of	filed, in examinati on

						a terminal carrier	
Multitest elektronische Systeme GmbH	China	CN200980000446	2/12/2009	CN101765784	6/26/2013	Device and method for aligning and holding a plurality of singulated semiconductor components in receiving pockets of a terminal carrier	patented
Multitest elektronische Systeme GmbH	Europe	EP09710349	2/12/2009	EP2135103	10/6/2010	Device and method for aligning and holding a plurality of singulated semiconductor components in receiving pockets of a terminal carrier	patented
Multitest elektronische Systeme GmbH	Germany (EP)	EP09710350	2/13/2009	502009000123	10/6/2010	Vorrichtung und Verfahren zum Ausrichten und Halten einer Mehrzahl singulierter Halbleiterbauelemente in Aufnahmetaschen eines Klemmträgers	validated (EP-patent EP2135103)
Multitest elektronische Systeme GmbH	Malta (EP)	EP09710351	2/14/2009	EP00194/2135103	10/6/2010	Device and method for aligning and holding a plurality of singulated	validated (EP-patent EP2135103)

						semiconductor components in receiving pockets of a terminal carrier	
Multitest elektronische Systeme GmbH	Italy (EP)	EP09710352	2/15/2009	19044BE/2011	10/6/2010	Device and method for aligning and holding a plurality of singulated semiconductor components in receiving pockets of a terminal carrier	validated (EP-patent EP2135103)
Multitest elektronische Systeme GmbH	France (EP)	EP09710352	2/15/2009	2135103	10/6/2010	Device and method for aligning and holding a plurality of singulated semiconductor components in receiving pockets of a terminal carrier	validated (EP-patent EP2135103)
Multitest elektronische Systeme GmbH	US	US671118	10/2/2008	US8303008	11/6/2012	Plunger for holding and moving electronic components, in particular ICs, with heat conducting body	patented
Multitest elektronische Systeme GmbH	Malaysia	PI20094228	10/2/2008	MY145021	12/15/2011	Plunger for holding and moving electronic components, in particular ICs, with heat conducting body	patented

Multitest elektronische Systeme GmbH	Korea, South	KR1020097022194	10/2/2008	KR101086934	11/29/2011	Plunger for holding and moving electronic components, in particular ICs, with heat conducting body	patented
Multitest elektronische Systeme GmbH	China	CN200880017147	10/2/2008	CN101680930	5/23/2012	Plunger for holding and moving electronic components, in particular ICs, with heat conducting body	patented
Multitest elektronische Systeme GmbH	Europe	EP08802776	10/2/2008	EP2195669	1/12/2011	Plunger for holding and moving electronic components, in particular ICs, with heat conducting body	validated (EP-patent EP2195669)
Multitest elektronische Systeme GmbH	Germany (EP)	EP08802776	10/2/2008		1/12/2011	Plunger zum Bewegen elektronischer Bauelemente, insbesondere ICs mit Wärmeleitkörper	validated (EP-patent EP2195669)
Multitest elektronische Systeme GmbH	Malta (EP)	EP08802776	10/2/2008	EP00254/2195669	1/12/2011	Plunger for holding and moving electronic components, in particular ICs, with heat conducting body	validated (EP-patent EP2195669)
Multitest elektronische Systeme GmbH	France (EP)	EP08802776	10/2/2008		1/12/2011	Plunger for holding and moving electronic	validated (EP-patent EP2195669)

						components, in particular ICs, with heat conducting body	
Multitest elektronische Systeme GmbH	Germany	DE102007047679	10/5/2007	DE102007047679	3/10/2011	Plunger zum Bewegen elektronischer Baueleme nte, insbesondere ICs mit Wärmeleitkörper	patented
Multitest elektronische Systeme GmbH	US	US599371	10/2/2008	US8232815	7/31/2012	Plunger for holding and moving electronic components in particular ICs	patented
Multitest elektronische Systeme GmbH	Malaysia	PI20093280	10/2/2008			Plunger for holding and moving electronic components in particular ICs	filed, in examination
Multitest elektronische Systeme GmbH	Korea, South	KR102009701777 0	10/2/2008	KR101193758	10/16/2012	Plunger for holding and moving electronic components in particular ICs	patented
Multitest elektronische Systeme GmbH	China	CN200880008015	10/2/2008	CN101646953	8/29/2012	Plunger for holding and moving electronic components in particular ICs	patented
Multitest elektronische Systeme GmbH	Europe	EP08802775	10/2/2008	EP2195668	1/12/2011	Plunger for holding and moving electronic components in particular ICs	patented

Multitest elektronische Systeme GmbH	Germany (EP)	EP08802775	10/2/2008		1/12/2011	Plunger zum Bewegen elektronischer Baueleme nte, insbesondere IC's	validated (EP-patent EP2195668)
Multitest elektronische Systeme GmbH	Malta (EP)	EP08802775	10/2/2008		1/12/2011	Plunger for holding and moving electronic components in particular ICs	validated (EP-patent EP2195668)
Multitest elektronische Systeme GmbH	France (EP)	EP08802775	10/2/2008		1/12/2011	Plunger for holding and moving electronic components in particular ICs	validated (EP-patent EP2195668)
Multitest elektronische Systeme GmbH	US	US526728	9/25/2008			Handler for electronic components, in particular ICs, comprising a pneumatic cylinder displacement unit for moving plungers	filed, in examination
Multitest elektronische Systeme GmbH	Malaysia	PI20093165	9/25/2008			Handler for electronic components, in particular ICs, comprising a pneumatic cylinder displacement unit for moving plungers	filed, in examination
Multitest elektronische Systeme GmbH	Japan	JP2010522269	9/25/2008	JP5140156	11/22/2012	Handler for electronic components, in particular ICs, comprising a	patented

						pneumatic cylinder displacement unit for moving plungers	
Multitest elektronische Systeme GmbH	Korea, South	KR1020097015729	9/25/2008	KR101203770	11/15/2012	Handler for electronic components, in particular ICs, comprising a pneumatic cylinder displacement unit for moving plungers	patented
Multitest elektronische Systeme GmbH	Philippines	PH12010500713	9/25/2008			Handler for electronic components, in particular ICs, comprising a pneumatic cylinder displacement unit for moving plungers	filed, in examination
Multitest elektronische Systeme GmbH	China	CN200880004146	9/25/2008	CN101611325	8/29/2012	Handler for electronic components, in particular ICs, comprising a pneumatic cylinder displacement unit for moving plungers	patented
Multitest elektronische Systeme GmbH	Europe	EP08838310	9/25/2008	EP2195671	1/12/2011	Handler for electronic components, in particular ICs, comprising a pneumatic cylinder displacement unit for moving	patented

						plungers	
Multitest elektronische Systeme GmbH	Germany (EP)	EP08838310	9/25/2008		1/12/2011	Handhabungsvorrichtung für elektronische Bauelemente, insbesondere ICs mit Pneumatikzylinderbewegungseinrichtung zum Verschieben von Plungern	validated (EP-patent EP2195671)
Multitest elektronische Systeme GmbH	Malta (EP)	EP08838310	9/25/2008		1/12/2011	Handler for electronic components, in particular ICs, comprising a pneumatic cylinder displacement unit for moving plungers	validated (EP-patent EP2195671)
Multitest elektronische Systeme GmbH	France (EP)	EP08838310	9/25/2008		1/12/2011	Handler for electronic components, in particular ICs, comprising a pneumatic cylinder displacement unit for moving plungers	validated (EP-patent EP2195671)
Multitest elektronische Systeme GmbH	US	US525894	9/25/2008	US8138779	3/20/2012	Handler for electronic components, in particular ICs, comprising circulating units, the temperature of which can	patented

						be controlled	
Multitest elektronische Systeme GmbH	Malaysia	PI200903141	9/25/2008	MY143309	4/15/2011	Handler for electronic components, in particular ICs, comprising circulating units, the temperature of which can be controlled	patented
Multitest elektronische Systeme GmbH	Japan	JP2010518572	9/25/2008	JP5140157	11/22/2012	Handler for electronic components, in particular ICs, comprising circulating units, the temperature of which can be controlled	patented
Multitest elektronische Systeme GmbH	Korea, South	KR10200970157 28	9/25/2008	KR101115161	2/1/2012	Handler for electronic components, in particular ICs, comprising circulating units, the temperature of which can be controlled	patented
Multitest elektronische Systeme GmbH	China	CN20088000405 6	9/25/2008	CN101606075	8/15/2012	Handler for electronic components, in particular ICs, comprising circulating units, the temperature of	patented

						which can be controlled	
Multitest elektronische Systeme GmbH	Europe	EP08837754	9/25/2008	EP2195670	1/19/2011	Handler for electronic components, in particular ICs, comprising circulating units, the temperature of which can be controlled	patented
Multitest elektronische Systeme GmbH	Germany (EP)	EP08837755	9/26/2008		1/19/2011	Handhabungsvorrichtung für elektronische Bauelemente, insbesondere IC's mit einer Mehrzahl von auf einer Umlaufbahn geführten Umlaufwagen	validated (EP-patent EP2195670)
Multitest elektronische Systeme GmbH	Malta (EP)	EP08837756	9/27/2008		1/19/2011	Handler for electronic components, in particular ICs, comprising circulating units, the temperature of which can be controlled	validated (EP-patent EP2195670)
Multitest elektronische Systeme GmbH	France (EP)	EP08837758	9/29/2008		1/19/2011	Handler for electronic components, in particular ICs, comprising circulating units, the temperatu	validated (EP-patent EP2195670)

						re of which can be controlled	
Multitest elektronische Systeme GmbH	US	US681735	9/25/2008	US8297433	10/30/2012	Handler for electronic components, in particular ICs, comprising a plurality of circulating carriages that are guided along a circulating track	patented
Multitest elektronische Systeme GmbH	Malaysia	PI2010000920	9/25/2008			Handler for electronic components, in particular ICs, comprising a plurality of circulating carriages that are guided along a circulating track	filed, in examination
Multitest elektronische Systeme GmbH	Korea, South	KR102010700346	9/25/2008			Handler for electronic components, in particular ICs, comprising a plurality of circulating carriages that are guided along a circulating track	filed, in examination
Multitest elektronische Systeme GmbH	Philippines	PH12010500715	9/25/2008			Handler for electronic components, in particular ICs, comprisin	filed, in examinati on

						g a plurality of circulatin g carriages that are guided along a circulatin g track	
Multitest elektronische Systeme GmbH	China	CN200880107624	9/25/2008	CN101802630	2/13/2013	Handler for electronic componen ts, in particular ICs, comprisin g a plurality of circulatin g carriages that are guided along a circulatin g track	patented
Multitest elektronische Systeme GmbH	Germany	DE102007047596	10/5/2007	DE102007047596	2/7/2013	Handhabu ngsvorric htung für elektronis che Baueleme nte, insbesond ere IC's mit einer Mehrzahl von auf einer Umlaufba hn geführten Umlaufwa gen	patented
Multitest elektronische Systeme GmbH	US	US681706	9/25/2008			Temperin g chamber for tempering electronic componen ts in particular Ics	filed, in examinati on
Multitest elektronische Systeme GmbH	Malaysia	PI2010001170	9/25/2008			Temperin g chamber for tempering electronic componen ts in particular Ics	filed, in examinati on

Multitest elektronische Systeme GmbH	Japan	JP2010527356	9/25/2008	JP5238031	4/5/2013	Temperin g chamber for tempering electronic componen ts in particular Ics	patented
Multitest elektronische Systeme GmbH	Korea, South	KR10201070062 83	9/25/2008	KR101259672	24.04.213	Temperin g chamber for tempering electronic componen ts in particular Ics	patented
Multitest elektronische Systeme GmbH	Philippines	PH12010500714	9/25/2008			Temperin g chamber for tempering electronic componen ts in particular Ics	filed, in examinati on
Multitest elektronische Systeme GmbH	China	CN200880110016	9/25/2008	CN101815952	3/27/2013	Temperin g chamber for tempering electronic componen ts in particular Ics	patented
Multitest elektronische Systeme GmbH	Germany	DE10200704777 2	10/5/2007	DE102007047772	7/21/2011	Temperier vorrichtun g zum Temperier en von elektronis chen Baueleme nten, insbesond er Ics	patented
Multitest elektronische Systeme GmbH	Malaysia	PI200700662	4/24/2008	MY142696	12/31/2010	Centering device for electronic componen ts, particularl y ICs	patented
Multitest elektronische Systeme GmbH	Japan	JP2010506821	4/24/2008	JP4948646	3/16/2012	Centering device for electronic componen ts, particularl y ICs	patented
Multitest elektronische Systeme GmbH	China	CN200880000094 2	4/24/2008	CN101548191	3/7/2012	Centering device for electronic componen ts, particularl y ICs	patented

Multitest elektronische Systeme GmbH	Germany	DE102007022690	5/11/2007	DE102007022690	11/18/2010	Zentriervorrichtung für elektronische Bauelemente, insbesondere ICs	patented
Multitest elektronische Systeme GmbH	US	US169899	7/9/2008	US7633304	12/15/2009	Device for testing electronic components, in particular ICs, having a sealing board arranged inside a pressure test chamber	patented
Multitest elektronische Systeme GmbH	Malaysia	PI20082478	7/4/2008	MY147709	1/15/2013	Device for testing electronic components, in particular ICs, having a sealing board arranged inside a pressure test chamber	patented
Multitest elektronische Systeme GmbH	Europe	EP08011535	6/25/2008	EP2015087	12/21/2011	Device for testing electronic components, in particular ICs, having a sealing board arranged inside a pressure test chamber	patented
Multitest elektronische Systeme GmbH	Germany (EP)	EP08011535	6/25/2008		12/21/2011	Vorrichtung zum Testen von elektronischen Bauelementen, insbesondere IC's mit innerhalb einer Drucktestkammer angeordne	validated (EP-patent EP2015087)

						tem Abdichtboard	
Multitest elektronische Systeme GmbH	Italy (EP)	EP08011535	6/25/2008		12/21/2011	Device for testing electronic components, in particular ICs, having a sealing board arranged inside a pressure test chamber	validated (EP-patent EP2015087)
Multitest elektronische Systeme GmbH	Germany	DE102007032557	7/12/2007	DE102007032557	9/16/2010	Vorrichtung zum Testen von elektronischen Bauelementen, insbesondere IC's mit innerhalb einer Drucktestkammer angeordnetem Abdichtboard	patented
Multitest elektronische Systeme GmbH	US	US668265	7/1/2008	US8449002	5/28/2013	Closure mechanism for pressure test chambers for testing electronic components, in particular Ics	patented
Multitest elektronische Systeme GmbH	Malaysia	PI20095449	7/1/2008	MY145169	12/30/2011	Closure mechanism for pressure test chambers for testing electronic components, in particular Ics	patented
Multitest elektronische Systeme GmbH	China	CN200880019417	7/1/2008	CN1717113366	6/26/2013	Closure mechanism for pressure test	patented

						chambers for testing electronic componen ts, in particular Ics	
Multitest elektronische Systeme GmbH	Europe	EP08759365	7/1/2008	EP2142935	8/25/2010	Closure mechanis m for pressure test chambers for testing electronic componen ts, in particular Ics	patented
Multitest elektronische Systeme GmbH	Malta (EP)	EP08759366	7/2/2008		8/25/2010	Closure mechanis m for pressure test chambers for testing electronic componen ts, in particular Ics	validated (EP-patent EP214293 5)
Multitest elektronische Systeme GmbH	Italy (EP)	EP08759367	7/3/2008		8/25/2010	Closure mechanis m for pressure test chambers for testing electronic componen ts, in particular Ics	validated (EP-patent EP214293 5)
Multitest elektronische Systeme GmbH	Germany	DE10200703255 9	7/12/2007	DE102007032559	9/9/2010	Verschlus smechanis mus für Drucktest kammern zum Testen von elektronis chen Baueleme nten, insbesond ere Ics	patented
Multitest elektronische Systeme GmbH	US	US294302	12/6/2007	US7946405	5/24/2011	Guide rail for electronic componen ts	patented
Multitest elektronische Systeme GmbH	Malaysia	PI20084151	12/6/2007	MY146934	10/15/2012	Guide rail for electronic componen ts	patented

Multitest elektronische Systeme GmbH	Germany	DE102006036291	8/3/2006	DE102006036291	5/24/2012	Verfahren und Kontaktiervorrichtung zum elektrischen Testen von elektronischen Bauelementen unter bestimmten Temperaturbedingungen	patented
Multitest elektronische Systeme GmbH	Europe	EP07786355	7/26/2007	EP2033002	4/21/2010	Verfahren und Kontaktiervorrichtung zum elektrischen Testen von elektronischen Bauelementen unter bestimmten Temperaturbedingungen	patented
Multitest elektronische Systeme GmbH	Italy (EP)	EP07786355	7/26/2007		4/21/2010	Contacting device for testing electronic components under specific temperature conditions	validated (EP-patent EP2033002)
Multitest elektronische Systeme GmbH	France (EP)	EP07786355	7/26/2007		4/21/2010	Contacting device for testing electronic components under specific temperature conditions	validated (EP-patent EP2033002)
Multitest elektronische Systeme GmbH	Austria (EP)	EP07786355	7/26/2007		4/21/2010	Contacting device for testing electronic components under specific temperature conditions	validated (EP-patent EP2033002)
Multitest elektronische Systeme GmbH	US	US990748	5/24/2007	US7683608	3/23/2010	Handler comprising an acceleration device for testing	patented

						electronic components	
Multitest elektronische Systeme GmbH	Malaysia	PI20080222	5/24/2007	MY146742	9/14/2012	Handler comprising an acceleration device for testing electronic components	patented
Multitest elektronische Systeme GmbH	Japan	JP2008555717	5/24/2007	JP4783832	7/15/2011	Handler comprising an acceleration device for testing electronic components	patented
Multitest elektronische Systeme GmbH	Korea, South	KR10200870095 99	5/24/2007	KR101043140	6/20/2011	Handler comprising an acceleration device for testing electronic components	patented
Multitest elektronische Systeme GmbH	Europe	EP07725540	5/24/2007	EP1891453	11/5/2008	Handler comprising an acceleration device for testing electronic components	patented
Multitest elektronische Systeme GmbH	Malta (EP)	EP07725540	5/24/2007		11/5/2008	Handler comprising an acceleration device for testing electronic components	validated (EP-patent EP189145 3)
Multitest elektronische Systeme GmbH	Germany	DE10200602534 1	5/31/2006	DE102006025341	4/16/2009	Handler mit Beschleunigungsvorrichtung zum Testen von elektronischen Bauelementen	patented
Multitest elektronische Systeme GmbH	US	US090419	3/29/2007	US7741861	6/22/2010	Test apparatus für the testing of electronic components	patented

Multitest elektronische Systeme GmbH	Malaysia	PI02025	3/29/2007	MY143637	6/15/2011	Test apparatus für the testing of electronic componen ts	patented
Multitest elektronische Systeme GmbH	Japan	JP2008555716	3/29/2007	JP5044575	7/20/2012	Test apparatus für the testing of electronic componen ts	patented
Multitest elektronische Systeme GmbH	Europe	EP07723765	3/29/2007	EP1902325	5/6/2009	Test apparatus für the testing of electronic componen ts	patented
Multitest elektronische Systeme GmbH	Italy (EP)	EP07723765	3/29/2007		5/6/2009	Test apparatus für the testing of electronic componen ts	patented
Multitest elektronische Systeme GmbH	Netherlands (EP)	EP07723765	3/29/2007		5/6/2009	Test apparatus für the testing of electronic componen ts	patented
Multitest elektronische Systeme GmbH	Germany	DE102006015363	4/3/2006	DE102006015363	4/16/2009	Testvorrichtung zum Testen von elektronischen Baueleme nten	patented
Multitest elektronische Systeme GmbH	US	US883874	11/30/2006	US7677383	3/16/2010	Guide path for electronic componen ts	patented
Multitest elektronische Systeme GmbH	Germany	DE102005032978	7/14/2005	DE102005032978	7/21/2011	Vorrichtung zum Zentrieren von elektronischen Baueleme nten	patented
Multitest elektronische Systeme GmbH	Germany	DE102006015365	4/3/2006	DE102006015365	11/19/2009	Verfahren und Vorrichtung zum Temperieren von elektronischen Baueleme nten	patented

Multitest elektronische Systeme GmbH	Europe	EP07723766	3/29/2007	EP1889133	2/4/2009	Method and device for tempering electronic components	patented
Multitest elektronische Systeme GmbH	Italy (EP)	EP07723766	3/29/2007		2/4/2009	Method and device for tempering electronic components	validated (EP-patent EP1889133)
Multitest elektronische Systeme GmbH	Austria (EP)	EP07723766	3/29/2007		2/4/2009	Method and device for tempering electronic components	validated (EP-patent EP1889133)
Multitest elektronische Systeme GmbH	Netherlands (EP)	EP07723766	3/29/2007		2/4/2009	Method and device for tempering electronic components	validated (EP-patent EP1889133)
Multitest elektronische Systeme GmbH	Malaysia	PI20080071	3/29/2007			Method and device for tempering electronic components	filed, notice to grant patent
Multitest elektronische Systeme GmbH	US	US288078	11/29/2005	US7841071	11/30/2010	Position-correction device for correcting the position of a component holder for electronic components	patented
Multitest elektronische Systeme GmbH	Germany	DE102004057776	11/30/2004	DE102004057776	8/18/2011	Lagekorrektureinrichtung zur Korrektur der Position eines Bauelementehalters für elektronische Bauelemente	patented
Multitest elektronische Systeme GmbH	US	US183974	7/19/2005	US7581410	9/1/2009	Low temperature testing device for electronic components	patented

Multitest elektronische Systeme GmbH	Germany	DE102004040527	8/20/2004	DE102004040527	3/30/2006	Kältetestvorrichtung für elektronische Baueleme nte	patented
Multitest elektronische Systeme GmbH	Germany	DE10216782	4/15/2002	DE10216782	3/10/2005	Führungsvorrichtung zum Andocken eines Testkopfes für elektronische Baueleme nte	patented
Multitest elektronische Systeme GmbH	US	US10413647	4/15/2003	US6836109	12/28/2004	Guiding apparatus for docking a testing head for electronic components	patented
Multitest elektronische Systeme GmbH	Germany	DE10216003	11/6/2003	DE10216003	3/10/2005	Dockingvorrichtung	patented
Multitest elektronische Systeme GmbH	Germany	DE19837564	8/19/1998	DE19837564	4/20/2000	Vereinzelungsvorrichtung für mikroelektronische Baueleme nte	patented

OWNER/ ASSIGNEE	COUNTRY	APPLICATION NUMBER	APPLICATION DATE	REGISTRATION/ PUBLICATION NUMBER	TITLE	STATUS
Multitest Elektronische Systems GmbH	USA	12/858,406	8/17/2010	8,683,680	ALIGN FIXTURE FOR ALIGNMENT OF AN ELECTRONIC COMPONENT	patented
Delaware Capital Formation, Inc.	Taiwan	99143251	12/10/2010	1432746	WIRING BOARD FOR TESTING LOADED PRINTED CIRCUIT BOARD	patented
Multitest Elektronische Systems GmbH	USA	12/858,400	8/17/2010	8,689,436	TWO ABUTTING SECTIONS OF AN ALIGN FIXTURE TOGETHER FLOATINGLY ENGAGING AN ELECTRONIC COMPONENT	patented
DTG International GmbH	USA	13/124,454	4/15/2011	8,704,545	DETERMINATION OF PROPERTIES OF AN ELECTRICAL DEVICE	patented
Multitest Elektronische Systems GmbH	USA	12/859,059	8/18/2010	8,717,048	SYSTEM FOR POST-PROCESSING OF ELECTRONIC COMPONENTS	patented
Delaware Capital Formation, Inc.	Philippines	1-2010-500312	9/17/2008	1-2010-500312	SPRING CONTACT ASSEMBLY	patented
DTG International GmbH	USA	12/681,295	4/1/2010	8,749,259	FULL GRID CASSETTE FOR A PARALLEL TESTER FOR TESTING A NON-COMPONENTED PRINTED CIRCUIT BOARD, SPRING CONTACT PIN FOR SUCH A FULL GRID CASSETTE AND ADAPTER FOR A PARALLEL TESTER FOR TESTING A NON-COMPONENTED PRINTED CIRCUIT BOARD	patented
Multitest Elektronische Systems	USA	13/950,156	7/24/2013	8,794,613	DEVICE AND METHOD FOR ALIGNING AND	patented

GmbH					HOLDING A PLURALITY OF SINGULATED SEMICONDUCTOR COMPONENTS IN RECEIVING POCKETS OF A TERMINAL CARRIER	
Delaware Capital Formation, Inc.	Taiwan	99145850	12/24/2010	1449917	TERMINAL FOR FLAT TEST PROBE	patented
Delaware Capital Formation, Inc.	Taiwan	99144733	12/20/2010	1452300	LOADED PRINTED CIRCUIT BOARD TEST FIXTURE AND METHOD FOR MANUFACTURING THE SAME	patented
Multitest Elektronische Systems GmbH	USA	14/184,606	2/19/2014		SYSTEM FOR POST-PROCESSING OF ELECTRONIC COMPONENTS	pending
DTG International GmbH	Taiwan	TW 103108783	3/12/2014		CROSS-BAR UNIT FOR A TEST APPARATUS FOR CIRCUIT BOARDS, AND TEST APPARATUS CONTAINING THE FORMER	pending
DTG International GmbH	USA	14/209,646	3/13/2014		CROSS-BAR UNIT FOR A TEST APPARATUS FOR CIRCUIT BOARDS, AND TEST APPARATUS CONTAINING THE FORMER	pending
Everett Charles Technologies LLC	USA	07/787936	11/05/1991	5,233,290	SWITCH PROBE	patented
Everett Charles Technologies LLC	USA	07/698724	05/10/1991	5,247,246	TESTING OF INTEGRATED CIRCUIT DEVICES ON LOADED PRINTED CIRCUIT BOARDS	patented
Everett Charles Technologies LLC	USA	07/827023	01/27/1992	5,252,916	PNEUMATIC TEST FIXTURE WITH SPRINGLESS TEST PROBES	patented

Everett Charles Technologies LLC	USA	07/824854	01/22/1992	5,270,641	DUAL SIDE ACCESS TEST FIXTURE	patented
Everett Charles Technologies LLC	USA	07/998554	12/30/1992	5,289,117	TESTING OF INTEGRATED CIRCUIT DEVICES ON LOADED PRINTED CIRCUIT	patented
Everett Charles Technologies LLC	USA	08/084755	06/30/1993	5,300,881	TEST FIXTURE	patented
Everett Charles Technologies LLC	USA	07/648453	01/31/1991	5,321,351	TEST FIXTURE ALIGNMENT SYSTEM	patented
Everett Charles Technologies LLC	USA	08/009133	01/26/1993	5,389,885	EXPANDABLE DIAPHRAGM TEST MODULES AND CONNECTORS	patented
Everett Charles Technologies LLC	USA	08/189693	02/01/1994	5,391,995	TWISTING ELECTRICAL TEST PROBE WITH CONTROLLED POINTING ACCURACY	patented
Everett Charles Technologies LLC	USA	07/990573	12/14/1992	5,408,189	TEST FIXTURE ALIGNMENT SYSTEM FOR PRINTED CIRCUIT BOARDS	patented
Everett Charles Technologies LLC	USA	08/010981	02/09/1993	5,416,428	MARKER PROBE	patented
Everett Charles Technologies LLC	USA	08/224006	04/05/1994	5,422,575	TEST FIXTURE WITH ADJUSTABLE BEARINGS AND OPTICAL ALIGNMENT SYSTEM	patented
Everett Charles Technologies LLC	USA	08/196588	02/10/1994	5,444,387	TEST MODULE HANGER FOR TEST FIXTURES	patented
Everett Charles Technologies LLC	USA	08/161250	12/03/1993	5,450,017	TEST FIXTURE HAVING TRANSLATOR FOR GRID INTERFACE	patented
Everett Charles Technologies LLC	USA	08/292054	08/16/1994	5,493,230	RETENTION OF TEST PROBES IN TRANSLATOR FIXTURES	patented
Everett Charles Technologies LLC	USA	08/462229	06/05/1995	5,557,211	VACUUM TEST FIXTURE FOR PRINTED CIRCUIT BOARDS	patented

Everett Charles Technologies LLC	USA	08/348565	12/01/1994	5,557,213	SPRING-LOADED ELECTRICAL CONTACT PROBE	patented
Everett Charles Technologies LLC	USA	08/593177	02/01/1996	5,633,598	TRANSLATOR FIXTURE WITH MODULE FOR EXPANDING TEST POINTS	patented
Everett Charles Technologies LLC	USA	08/558687	11/16/1995	5,641,315	TELESCOPING SPRING PROBE	patented
Everett Charles Technologies LLC	USA	08/532400	09/22/1995	5,663,655	ESD PROTECTION FOR UNIVERSAL GRID TYPE TEST FIXTURES	patented
Everett Charles Technologies LLC	USA	08/561395	1/21/1995	5,667,410	ONE-PIECE COMPLIANT PROBE	patented
Everett Charles Technologies LLC	USA	08/531720	09/21/1995	5,729,146	QUICK STACKING TRANSLATOR FIXTURE	patented
Everett Charles Technologies LLC	USA	08/515455	08/15/1995	5,744,948	PRINTED CIRCUIT BOARD HANDLING DEVICE	patented
Everett Charles Technologies LLC	USA	08/758911	12/02/1996	5,798,654	TRANSLATOR FIXTURE WITH MODULE FOR EXPANDING TEST POINTS	patented
Everett Charles Technologies LLC	USA	D/906278	06/26/1992	D343,802	COAXIAL TEST PROBE	patented
Everett Charles Technologies LLC	USA	D/065622	01/31/1997	D395,016	COAXIAL TEST PROBE WITH QUADRATURE GROUND PROVISION	patented
LTX Corporation	USA	10/698299	10/31/2003	7,196,566	High-resolution variable attenuation device	patented

EXHIBIT C

Trademarks

See Attached

Exhibit C
Trademarks

Registered Trademarks of Xcerra Corporation

Jurisdiction	Registration No.	Registration Date	Filing Date	Registered Owner	Mark
USA	2152177	4/21/1998	3/03/1997	Xcerra Corporation	CREDENCE (word mark)
USA	4003369	7/26/2011	3/10/2010	Xcerra Corporation	I M A (design and letters)
USA	4215510	9/25/2012	12/20/2011	Xcerra Corporation	LTXC (word mark)
USA	3946845	4/19/2011	3/10/2010	Xcerra Corporation	Xcerra (word mark)
USA	3946846	4/19/2011	3/10/2010	Xcerra Corporation	LTXCredence (word mark logo)
USA	4029508	9/20/2011	3/10/2010	Xcerra Corporation	XC (word mark logo)
EU	1042953	5/27/2010	4/20/2010	Xcerra Corporation	XCERRA (word mark)
JAPAN	1042953	11/8/2010	4/20/2010	Xcerra Corporation	XCERRA (word mark)
SINGAPORE	1042953	8/29/2012	4/20/2010	Xcerra Corporation	XCERRA (word mark)
ARMENIA	1042953	7/15/2011	4/20/2010	Xcerra Corporation	XCERRA (word mark)
CHINA	1042953	6/20/2011	4/20/2010	Xcerra Corporation	XCERRA (word mark)
KOREA	1042953	12/1/2011	4/20/2010	Xcerra Corporation	XCERRA (word mark)
KOREA	40-0418784	8/27/1998	8/30/1997	Credence Systems Corporation	CREDENCE (word mark)
CHINA	1257021	3/21/2009	1/5/2009	Credence Systems Corporation	CREDENCE (word mark)

Pending Trademark Applications of Xcerra Corporation

Jurisdiction	Application No.	Filing Date	Applicant	Mark
USA	86/222,472	3/16/2014	XCERRA CORPORATION	XCERRA (word mark)
USA	86/225,658	3/19/2014	XCERRA CORPORATION	XCERRA (logo)

Trademarks

OWNER	COUNTRY	APPLICATION NUMBER	FILING DATE	REGISTRATION NUMBER	REGISTRATION DATE	MARK
Delaware Capital Formation, Inc.	United States	75-711658	21-May-99	2571852	21-May-02	BANTAM
Delaware Capital Formation, Inc.	United Kingdom	2214278	15-Nov-99	2214278	07-Jul-00	BANTAM
Delaware Capital Formation, Inc.	Taiwan	88057311	18-Nov-99	930664	16-Feb-01	Bantam
Delaware Capital Formation, Inc.	Japan	2002-042399	23-May-02	4831504	07-Jan-05	BANTAM
Delaware Capital Formation, Inc.	European	1382779	12-Nov-99	1382779	20-Dec-00	BANTAM
Delaware Capital Formation, Inc.	United States	75-711660	21-May-99	2553252	26-Mar-02	BANTAM PAK
Delaware Capital Formation, Inc.	United Kingdom	2214276	15-Nov-99	2214276	30-Jun-00	BANTAM PAK
Delaware Capital Formation, Inc.	Taiwan	88057310	18-Nov-99	936054	16-Feb-01	Bantam Pak
Delaware Capital Formation, Inc.	European	1383116	12-Nov-99	1383116	11-Dec-00	BANTAM PAK
Delaware Capital Formation, Inc.	Germany	P 32837 9WZ	21-Jun-85	1090880	28-Apr-86	BIASING BALL
Delaware Capital Formation, Inc.	France	747531	14-Jun-85	1312722	14-Jun-85	BIASING BALL
Delaware Capital Formation, Inc.	United States	73-518861	23-Jan-85	1351509	30-Jul-85	BIASING-BALL
Delaware Capital Formation, Inc.	Canada	0544107	20-Jun-85	TMA320636	14-Nov-86	BIASING-BALL
Delaware Capital Formation, Inc.	United States	76-401873	30-Apr-02	2738808	15-Jul-03	DURAPAK
Delaware Capital Formation, Inc.	Taiwan	17226	02-May-02	1043345	16-May-03	DURAPAK
Delaware Capital Formation, Inc.	Japan	2002-037770	09-May-02	4651696	07-Mar-03	DURAPAK
Delaware Capital Formation, Inc.	China	3208411	12-Jun-02	3208411	14-Oct-03	DuraPak
Delaware Capital Formation, Inc.	Canada	1139359	30-Apr-02	TMA651714	27-Oct-05	DURAPAK
Delaware Capital Formation, Inc.	Taiwan	94014990	01-Apr-05	01197346	16-Feb-06	ECT
Delaware Capital Formation, Inc.	Singapore	T05/04594E	29-Mar-05	T05/04594E	18-Oct-05	ECT
Delaware Capital Formation, Inc.	Singapore	T05/045921	29-Mar-05	T05/045921	26-Jul-05	ECT
Delaware Capital Formation, Inc.	Hong Kong	Not yet filed	Not yet filed			ECT
Delaware Capital Formation, Inc.	China	4634094	29-Apr-05	4634094	21-Dec-08	ECT
Delaware Capital Formation, Inc.	China	4634096	29-Apr-05	4634096	28-Oct-09	ECT
Delaware Capital Formation, Inc.	United States	78-593816	23-Mar-05	3167563	07-Nov-06	ECT and Design
Delaware Capital Formation, Inc.	European	4363073	30-Mar-05	4363073	18-Apr-06	ECT and design
Delaware Capital Formation, Inc.	China	4634093	29-Apr-05	4634093	28-Oct-09	ECT and design
Delaware Capital Formation, Inc.	United States	78-593835	23-Mar-05	3167564	07-Nov-06	ECT Block Letters
Delaware Capital Formation, Inc.	Taiwan	94014991	01-Apr-05	01197347	16-Feb-06	ECT stylized and design

Delaware Capital Formation, Inc.	Singapore	T05/04591J	29-Mar-05	T05/04591J	01-Feb-06	ECT stylized and design
Delaware Capital Formation, Inc.	Singapore	T05/04590B	29-Mar-05	T05/04590B	16-Jan-06	ECT stylized and design
Delaware Capital Formation, Inc.	Hong Kong	300393246	29-Mar-05	300393246	24-Aug-05	ECT stylized and design
Delaware Capital Formation, Inc.	China	4634095	29-Apr-05	4634095	21-Dec-08	ECT stylized and design
Delaware Capital Formation, Inc.	United States	78-213082	10-Feb-03	3068926	14-Mar-06	ELIMINATOR
Delaware Capital Formation, Inc.	China	2001032801	09-Mar-01	2018115	14-Oct-04	ELIMINATOR
Delaware Capital Formation, Inc.	United States	76-679657	19-Jul-07	3456134	01-Jul-08	ESH Block Letters
Delaware Capital Formation, Inc.	United States	74-243815	06-Feb-92	1838309	31-May-94	EVERETT CHARLES TECHNOLOGIES
Delaware Capital Formation, Inc.	Taiwan	94014483	30-Mar-05	1208763	01-May-06	Everett Charles Technologies
Delaware Capital Formation, Inc.	Singapore	T05/04125G	28-Mar-05	T05/04125G	28-Dec-05	Everett Charles Technologies
Delaware Capital Formation, Inc.	Singapore	T05/04124I	28-Mar-05	T05/04124I	20-Sep-05	Everett Charles Technologies
Delaware Capital Formation, Inc.	Mexico	709888	01-Apr-05	884973	31-May-05	Everett Charles Technologies
Delaware Capital Formation, Inc.	Mexico	714727	28-Apr-05	888348	24-Jun-05	Everett Charles Technologies
Delaware Capital Formation, Inc.	Japan	H10-099459	20-Nov-98	4746192	06-Feb-04	EVERETT CHARLES TECHNOLOGIES
Delaware Capital Formation, Inc.	Hong Kong	300393237	29-Mar-05	300393237	04-Aug-05	Everett Charles Technologies
Delaware Capital Formation, Inc.	European	4362927	30-Mar-05	004362927	18-Apr-06	Everett Charles Technologies
Delaware Capital Formation, Inc.	China	4541448	15-Mar-05	4541448	07-Oct-08	Everett Charles Technologies
Delaware Capital Formation, Inc.	China	4551526	21-Mar-05	4551526	21-Jan-08	Everett Charles Technologies
Delaware Capital Formation, Inc.	Brazil	827313985	07-Apr-05	827313985	06-Nov-07	Everett Charles Technologies
Delaware Capital Formation, Inc.	Brazil	827313977	07-Apr-05	827313977	20-Nov-07	Everett Charles Technologies
Delaware Capital Formation, Inc.	United States	73-642017	28-Jan-87	1467094	01-Dec-87	FASTITE
Delaware Capital Formation, Inc.	United States	85/925778	07-May-13			Laserwire
Delaware Capital Formation, Inc.	Korea, South	4020040044233	30-Sep-04	4006365650000	27-Oct-05	MINI MITE
Delaware Capital Formation, Inc.	United States	76-401874	30-Apr-02	2680883	28-Jan-03	MINI-MITE
Delaware Capital Formation, Inc.	Taiwan	17228	02-May-02	1043346	16-May-03	MINI-MITE
Delaware Capital Formation, Inc.	Canada	1139360	30-Apr-02	TMA648760	22-Sep-05	MINI-MITE
Delaware Capital Formation, Inc.	United States	72-346959	22-Dec-69	916181	13-Jul-71	POGO
Delaware Capital Formation, Inc.	United Kingdom	1193106	29-Mar-83	1193106	02-Jan-85	POGO
Delaware Capital Formation, Inc.	Taiwan	87050094	14-Oct-98	922362	01-Jan-01	Pogo
Delaware Capital Formation, Inc.	Japan	H07-96393	21-Sep-95	4090608-2	12-Dec-97	Pogo

Delaware Capital Formation, Inc.	Japan	1998-087300	13-Oct-98	4537490	18-Jan-02	POGO
Delaware Capital Formation, Inc.	Italy	33655C/83	21-Apr-83	1055588	03-Nov-86	POGO
Delaware Capital Formation, Inc.	Germany	P 30191 9WZ	07-Apr-83	1056822	05-Dec-83	POGO
Delaware Capital Formation, Inc.	France	660649	07-Apr-83	1232477	05-Apr-93	POGO
Delaware Capital Formation, Inc.	Canada	501198	31-Mar-83	288699	09-Mar-84	POGO
Delaware Capital Formation, Inc.	United Kingdom	B1336919	29-Feb-88	B1336919	08-Feb-91	ROBOPROBE
Delaware Capital Formation, Inc.	United States	73-576583	06-Jan-86	1608864	07-Aug-90	TTI TESTRON and Design
Delaware Capital Formation, Inc.	Taiwan	97022414	13-May-08	01353722	16-Mar-09	Valitron
Delaware Capital Formation, Inc.	Singapore	T08/05897E	06-May-08	T0805897E	06-May-08	Valitron
Delaware Capital Formation, Inc.	Malaysia	08008772	06-May-08	08008772	15-Apr-10	Valitron
Delaware Capital Formation, Inc.	Korea, South	40-2008-0022203	08-May-08	4007771060000	23-Jan-09	Valitron
Delaware Capital Formation, Inc.	Japan	2008-035515	08-May-08	5176251	24-Oct-08	Valitron
Delaware Capital Formation, Inc.	India	1686564	13-May-08	1686564	07-Feb-11	Valitron
Delaware Capital Formation, Inc.	Hong Kong	301109718	06-May-08	301109718	16-Dec-08	Valitron
Delaware Capital Formation, Inc.	European	006854848	14-Apr-08	006854848	29-Jan-09	Valitron
Delaware Capital Formation, Inc.	China	6715806	12-May-08	6715806	07-Jun-10	Valitron
Delaware Capital Formation, Inc.	United States	77-406694	26-Feb-08	3538480	25-Nov-08	VALITRON Block Letters
Delaware Capital Formation, Inc.	WIPO	1032674	04-Mar-10	1032674	04-Mar-10	ZIP
Delaware Capital Formation, Inc.	Vietnam	1032674	04-Mar-10	1032674	04-Mar-10	Zip
Delaware Capital Formation, Inc.	Singapore	1032674	04-Mar-10	1032674	04-Mar-10	Zip
Delaware Capital Formation, Inc.	Korea, South	1032674	04-Mar-10	1032674	04-Mar-10	Zip
Delaware Capital Formation, Inc.	Japan	1032674	04-Mar-10	1032674	04-Mar-10	Zip
Delaware Capital Formation, Inc.	Hong Kong	301558422	09-Mar-10	301558422	11-Aug-10	Zip
Delaware Capital Formation, Inc.	European	1032674	04-Mar-10	1032674	04-Mar-10	Zip
Delaware Capital Formation, Inc.	China	1032674	04-Mar-10	1032674	04-Mar-10	Zip
Delaware Capital Formation, Inc.	Canada	1472045	05-Mar-10	TMA835542	01-Nov-12	Zip
Delaware Capital Formation, Inc.	United States	77-884604	02-Dec-09	3807010	22-Jun-10	ZIP Block Letters
Delaware Capital Formation, Inc.	Taiwan	99010063	08-Mar-10	01432224	01-Oct-10	ZIP Block Letters
Delaware Capital Formation, Inc.	Philippines	4-2010-002712	10-Mar-10	42010002712	03-Mar-11	ZIP Block Letters
Delaware Capital Formation, Inc.	Malaysia	2010004046	09-Mar-10	2010004046	05-Nov-12	ZIP Block Letters
Delaware Capital Formation, Inc.	India	1937409	17-Mar-10			ZIP Block Letters
Delaware Capital Formation, Inc.	Brazil	830553894	29-Mar-10			ZIP Block Letters
Everett Charles Technologies, Inc.	United States	75-747911	12-Jul-99	2513864	4-Dec-01	Harbor Electronics

Everett Charles Technologies, Inc.	United States	78-416268	10-May-04	3534112	18-Nov-08	Harbor Electronics block letters
Everett Charles Technologies, Inc.	United States	78-119699	4-Apr-02	2856747	22-Jun-04	Harbor Electronics, Inc (and Design)
atg Luther & Maelzer GmbH	European Union	11274081	10/17/2012			SmartStep
atg Luther & Maelzer GmbH	International Registration	011274081_01	3/1/2013			SmartStep
DTG International GmbH	Taiwan, R.O.C.	101065778	11/20/2012			SmartStep
atg Luther & Maelzer GmbH	European Union	11274032	10/17/2012			FlexStep
atg Luther & Maelzer GmbH	International Registration	011274032_01	3/1/2013			Flexstep
DTG International GmbH	Taiwan, R.O.C.	101065777	11/20/2012			FlexStep
atg Luther & Maelzer GmbH	Germany	395 20 443.7	05/15/1995	395 20 443		atg
atg test systems GmbH & Co. KG	Japan	H08-129286	11/15/1996	4178459		atg
atg test systems GmbH & Co. KG	Korea	4.01996E+12	07/18/1996	4.00387E+12		atg
atg test systems GmbH & Co. KG	Korea	4.11996E+12	07/18/1996	4.10048E+11		atg
atg Luther & Maelzer GmbH	Germany	398 44 048.4/09	4/8/1998	398 44 048		EXALINE
atg test systems GmbH & Co. KG	European Union	16790	1/4/1996			atg (Dreieck)
atg test systems GmbH & Co. KG	European Union	2083400	01/18/2001	2083400		atg
atg Luther & Maelzer GmbH	China	2001083235	05/21/2001	1993476		atg (int class 9)
atg test systems GmbH & Co. KG	China	2001083236	05/21/2001	2011640		atg (int class 42)
atg test systems GmbH & Co. KG	Taiwan, R.O.C.	90021454	05/29/2001	998399		„atg" (int. Class 9)
atg test systems GmbH & Co. KG	Taiwan, R.O.C.	90021455	05/29/2001	173108		„atg" (int. Class 42)
atg test systems GmbH & Co. KG	Taiwan, R.O.C.	91026808	05/29/2001			„atg" (int. Class 37)
atg test systems GmbH	China	5084494	12/26/2005	5084494		LaTest
atg Luther & Maelzer GmbH	Germany	307 10 983.6 / 09	02/21/2007	307 10 983.6		LaTest (Wortmarke)
atg test systems GmbH	International Registration	936 346	02/21/2007	936 346		LaTest (Wortmarke)
atg test systems GmbH	Japan	2005-120558	12/22/2005	4,999,861		LaTest, class 09
atg test systems GmbH	Korea	40-2005-0060502	12/23/2005	40-0698104		LaTest (class 9)
atg test systems GmbH	Taiwan, R.O.C.	94061913	12/22/2005	1225621		LaTest (word mark) in class 9
atg Luther & Maelzer GmbH	U.S.A.	77/254,473	08/14/2007	3,470,797		LaTest (Wortmarke)
atg test systems GmbH	European Union	5013297	11/4/2006			A6 (3D-Marke), Beschwerdesache R0421/2007-1
atg test systems GmbH	China	6271019	11/9/2007			EXAMAT, class 9
atg test systems GmbH	European Union	5991336	12/6/2007	5991336		EXAMAT
atg test systems GmbH	Taiwan, R.O.C.	96040475	08/23/2007	1312440		EXAMAT, class 9
atg Luther &	Germany	307 40 540.0 / 09	06/21/2007	307 40 540		MicroShort Detection

Maelzer GmbH						(Wortmarke)
atg Luther & Maelzer GmbH	Austria	AM 7901/2007	11/15/2007			MicroShort Detection (Wortmarke)
atg Luther & Maelzer GmbH	China	6405163	11/28/2007			MicroShort Detection
atg Luther & Maelzer GmbH	Italy	MI2007C011880	11/19/2007			MicroShort Detection (Wortmarke)
atg Luther & Maelzer GmbH	Korea	2008-0046559	12/12/2007	40-0790096		MicroShort Detection
Luther & Maelzer GmbH & Co. KG	China	3995320	5/4/2004	3995320		LM, Bildmarke, Klasse 9
atg Luther & Maelzer GmbH	European Union	7014491	06/25/2008			„LM", Bildmarke
Luther & Maelzer GmbH & Co. KG	Hong Kong	300127692	12/16/2003			LM, Wortmarke, Klasse 9
Luther & Maelzer GmbH & Co. KG	Japan	2004-041147	04/30/2004	4829224		LM, Bildmarke, Klasse 9
Luther & Maelzer GmbH & Co. KG	Korea	40-2004-0051990	11/17/2004	636624		LM, Bildmarke, Klasse 9
Luther & Maelzer GmbH & Co. KG	Taiwan, R.O.C	92071707	12/12/2003	11422225		LM, Klasse 9
Luther & Maelzer GmbH & Co. KG	Korea	40-2004-0051987	11/17/2004	636621		LM40
Luther & Maelzer GmbH & Co. KG	Korea	40-2004-0051989	11/17/2004	636623		LM400
Luther & Maelzer GmbH & Co. KG	China	785175	07/15/2002	G785175		LUTHER & MAELZER, Klasse 7
Luther & Maelzer GmbH & Co. KG	Germany	302 25 895.7 / 07	05/24/2002	302 25 895		Luther & Maelzer (Wortmarke)
Luther & Maelzer GmbH & Co. KG	European Union	2711190	05/24/2002	2711190		Luther & Maelzer (Wortmarke)
Luther & Maelzer GmbH & Co. KG	International Registration	785 175	07/15/2002	785 175		Luther & Maelzer (Wortmarke)
Luther & Maelzer GmbH & Co. KG	China	4356358	10/11/2004	4356358		Luther & Maelzer in chinesischen Schriftzeichen, Klasse 9
Luther & Maelzer GmbH & Co. KG	Hong Kong	300257698	07/28/2004	300257698		Luther & Maelzer in chinesischen Schriftzeichen, Klasse 09
Luther & Maelzer GmbH & Co. KG	Taiwan, R.O.C.	93035238	07/29/2004	1163618		Luther & Maelzer in chinesischen Schriftzeichen, Klasse 9
atg Luther & Maelzer GmbH	U.S.A.	76-447,025	5/9/2002	2,785.821		Luther & Maelzer (Wortmarke)
Luther & Maelzer GmbH & Co. KG	China	4033553	04/23/2004	ZC4033553ZC		Picomat (Wortmarke)
Luther & Maelzer GmbH & Co. KG	Germany	1116411	05/22/1987	1116411		QUICKTEST (Wort-/Bildmarke)
Luther & Maelzer GmbH & Co. KG	Japan	2004-015420	02/20/2004	4794712		Picomat (Wortmarke)
Luther & Maelzer GmbH & Co. KG	Korea	2004-0007279	02/19/2004	608268		Picomat (Wortmarke)
Luther & Maelzer GmbH & Co. KG	Korea	2002-0028027	06/18/2002	561639		Luther & Maelzer (Wortmarke)
Multitest	Germany			304 42 975	11/24/2004	InStrip
Multitest	China			4485398, 4485397, 4485396 and 4485395	07 11 2007 and 28.08.2008	InStrip
Multitest	Malaysia			4019393, 4019394, 4019395, 4019396	10.12.2004	InStrip
Multitest	Philippines			4-2004-11874	12/31/2005	InStrip

Multitest	Taiwan			01228195, 01191834, 01193077, 01193229	16.01.2006 and 16 09 2006	InStrip
Multitest	WIPO			858127	3/10/2005	InStrip
Multitest	USA			3095898	5/23/2006	InStrip
Multitest	Singapore			T05/16753F, T05/16752H, T05/16754D	10.03.2005	InStrip
Multitest	Germany			304 42 976	11/24/2004	InSite
Multitest	China			4485393	8/28/2008	InSite
Multitest	Malaysia			4019398	10.12.2004	InSite
Multitest	Taiwan			1175336, 1187692, 1187836	12/16/2005	InSite
Multitest	WIPO			867517	3/10/2005	InSite
Multitest	Singapore			T05/23979J, T05/23977D, T05/23978B	10 03 2005	InSite
Multitest	Germany			304 42 977	11/24/2004	QuickDock
Multitest	China			4485391, 4485390, 4485389	07.07.2007, 28.08.2008, 21.11.2008	QuickDock
Multitest	Malaysia			4019400, 40194001, 40194002	10.12.2004	QuickDock
Multitest	Philippines			11876	2007 Declaration of Actual Use was not filed	QuickDock
Multitest	Taiwan			1228262, 1193078, 1180288	16.01.2006, 01.11.2005, 16.09.2006	QuickDock
Multitest	WIPO			867518	3/10/2005	QuickDock
Multitest	USA			3133336	22.08.2006 Declaration of Actual Use was not filed	QuickDock
Multitest	Singapore			T05/23980D, T05/23981B, T05/23982J	10.03.2005	QuickDock
Multitest	Germany			304 42 978	10/26/2004	Dura
Multitest	China			4485380, 4485381, 4485379	8/28/2008	Dura
Multitest	Malaysia			4019403, 4019404, 4019405	10.12.2004	Dura
Multitest	Philippines			4-2004-11875	13.11.2006 Declaration of Actual Use was not filed	Dura
Multitest	Taiwan			1185878, 1187664, 1137838	12/16/2005	Dura
Multitest	WIPO			867619	3/10/2005	Dura
Multitest	USA			3133337	8/22/2006	Dura

Multitest	Singapore			T05/24014D, T05/24015B, T05/24016J	10.03.2005	Dura
Multitest	Germany			304 42 979	1/13/2005	Multicare
Multitest	China			4485366	12/7/2008	Multicare
Multitest	Malaysia			4019407, 4019409	12/10/2004	Multicare
Multitest	Philippines			11878	Declaration of Actual Use was not filed	Multicare
Multitest	Taiwan			1180115, 1180251, 1193228	01.11.2005, 16.01.2006	Multicare
Multitest	WIPO			873286	3/10/2005	Multicare
Multitest	Singapore			T06/01690F, T06/01691D, T06/01692B	3/10/2005	Multicare
Multitest	EU			4604021	Withdrawn	Multitest
Multitest	EU			5582457	1/18/2008	Multitest
Multitest	EU			8280927	11/22/2009	nanoKelvin
Multitest	USA			3878511	11/23/2010	nanoKelvin
Multitest	EU			8308009	11/24/2009	FORTA
Multitest	USA			3855475	10/5/2010	FORTA
Multitest	EU			8280968	Withdrawn	ECON
Multitest	USA			77729245 (serial number)	Discontinued	ECON
Multitest	EU			8990178	9/29/2010	plug & yield
Multitest	USA			3950145	4/26/2011	plug & yield
Multitest	Singapore			T1005411F	29.04.2010	plug & yield
Multitest	EU			8480493	1/27/2010	inCarrier
Multitest	Malaysia			Anmeldenr. 2010001615 2010001616 2010001614		inCarrier
Multitest	Taiwan			1463510	7/1/2011	inCarrier
Multitest	WIPO			1027637	9/23/2009	inCarrier
Multitest	USA			3916208	2/8/2011	inCarrier
Multitest	Singapore			T1002039D	9/23/2009	inCarrier
Multitest	EU			10971571	10/24/2012	Triton

Everett Charles Technologies LLC	USA	76/401873	30-Apr-2002	2738808	15-Jul-2003	DURAPAK
Everett Charles Technologies LLC	USA	77/254473	27-Aug-2007	3470797	22-Jul-2008	LATEST
Everett Charles Technologies LLC	USA	78/416268	10-May-2004	3534112	18-Nov-2008	HARBOR ELECTRONICS
LTX-Credence Corporation	USA	74/217835	01-Nov-1991	1742874	29-Dec-1992	LTX
LTX-Credence Corporation	USA	75/587200	12-Nov-1998	2696016	11-Mar-2003	EMISCOPE